

Recent Advances of Industrial AI for Smart and Resilient Industrial Systems

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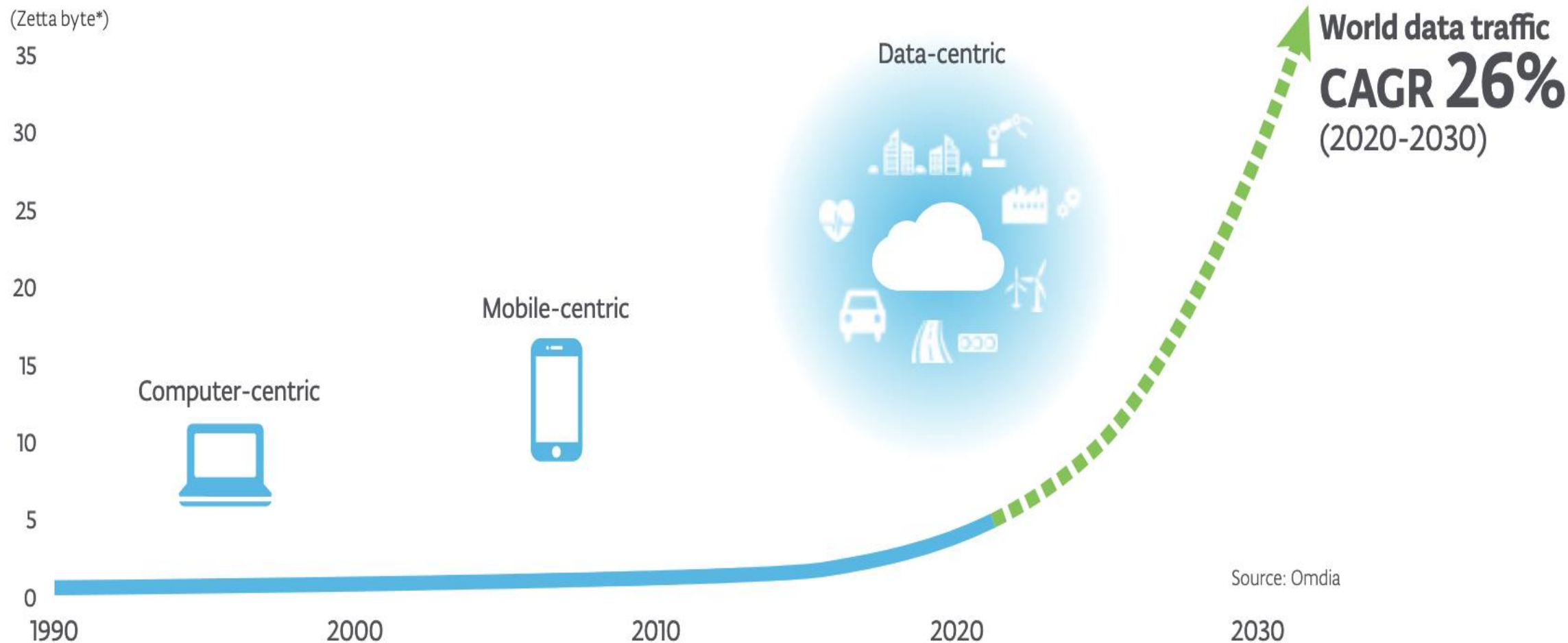
Outline

- 1. Trends of Data Centric Systems and Unmet Needs**
- 2. Trends of AI and Industrial AI Systems**
- 3. Some Examples**
- 4. Training of New Breed of Industrial AI Engineers**

Outline

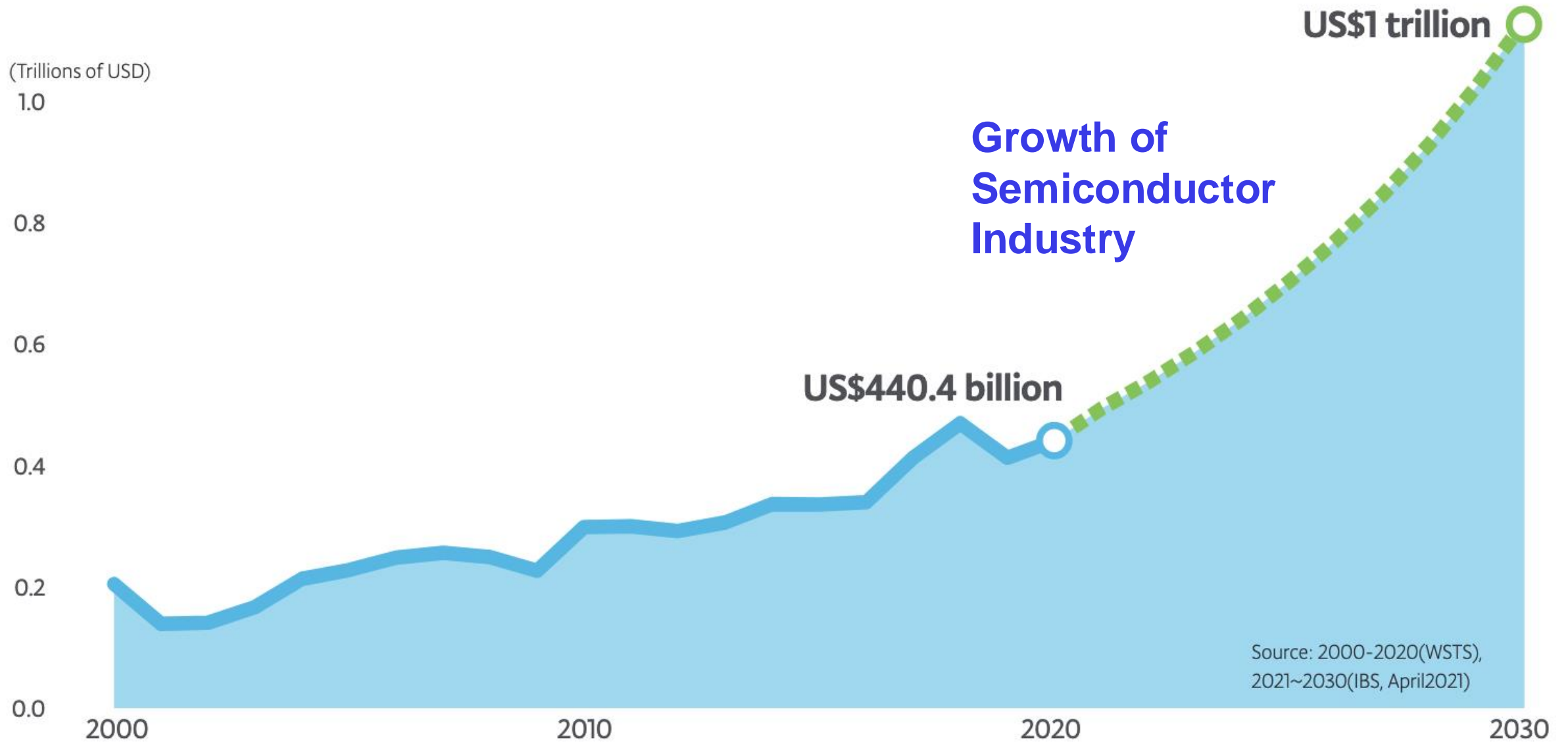
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Trends of Connected Systems and Data Driven Economy



*Zettabyte: 1Zettabyte = 1021byte, 1Zettabyte is said to be "the number of sand grains on sandy beaches around the world"

Growth of Semiconductor Industry



Industrial AI and Data-Centric Metrology for Highly Connected and Complex Industrial System @ Univ. of Maryland



Fleet of Jet Engines

Wind Farm

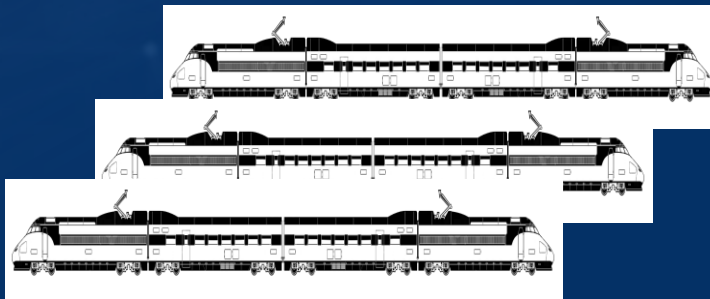


Field Equipment

Fleet of EVs



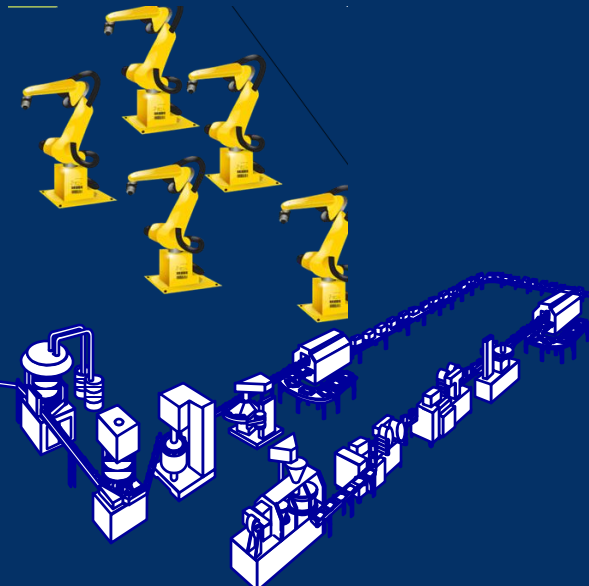
Fleet of Rail Systems



Advanced Fab.



Connected Production Machines and Smart Manufacturing Systems



Challenges and Needs of AI in Complex Industrial System

Avoid

**Utilize New Knowledge/
Technologies
For Value-added
Improvement**

**Value Creation
using
Smarter Information
For Unknown
Knowledge**

Solve

**Problem Solving
Through Continuous
Improvement and
Standard Work**

**Utilize New
Methods/
Techniques to Solve
The Unknown
Problems**

Visible

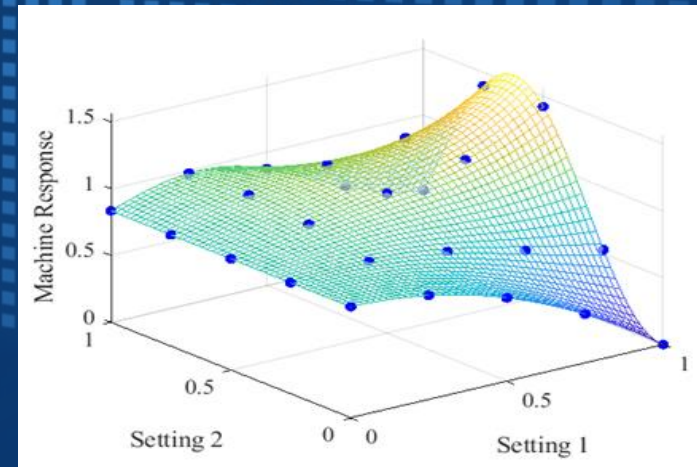
Invisible

Data and Modeling Issues in Complex Industrial Systems

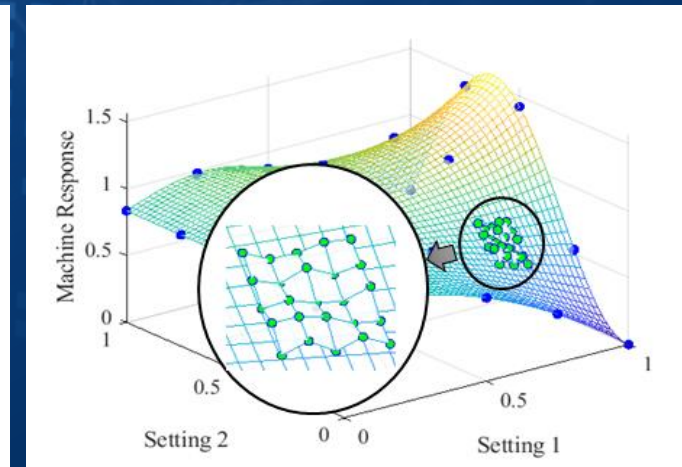
Data Usability



Reference Source



Target Source



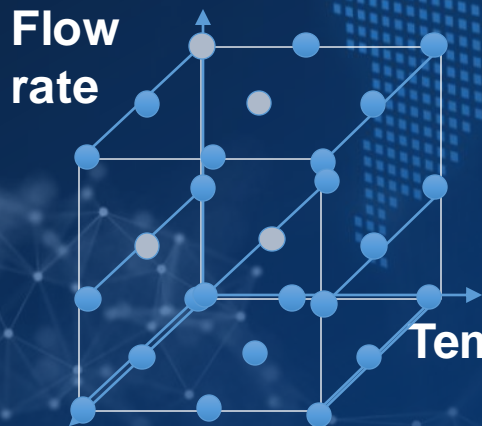
Source	Reference Source	Target Source
Data Quantity	✓ High Volume	✓ Low Volume
Data Quality	✓ High quality	<ul style="list-style-type: none"> ✓ Dynamic ✓ Time-restricted ✓ Drifted / Shifted ✓ Noisy
Data Representativeness	✓ Comprehensive	<ul style="list-style-type: none"> ✓ Local ✓ High variation
Data Availability	✓ High availability	✓ Low availability

Need Better Data Representation Methodology

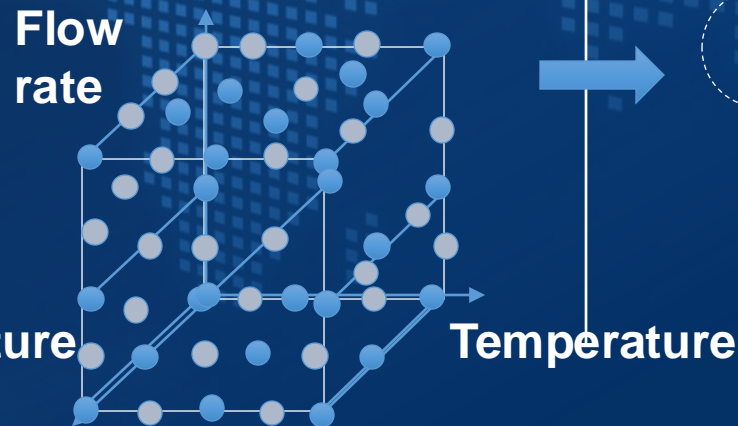
Limited Data Scenario

- Difficult for modeling
- Usually need data augmentation strategy to generate more data
- Whole data space is not fully explored

Traditional DOE methods



Sampling methods



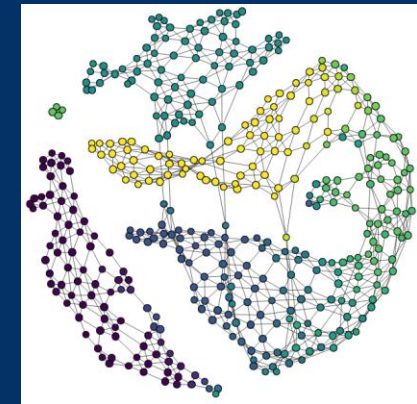
High Volume Data Scenario

- High model complexity
- Labeling would be demanding work for user
- Computation expensive

clustering methods



Topological Data Analysis



Pressure

Pressure

Low Complexity/Quantity

High Complexity/Quantity

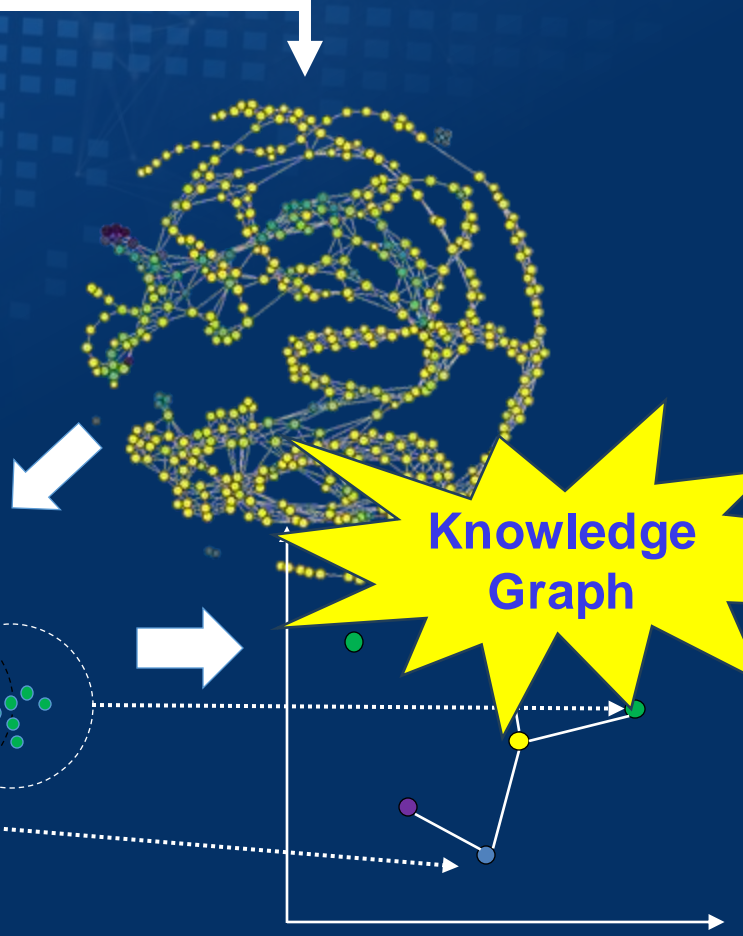
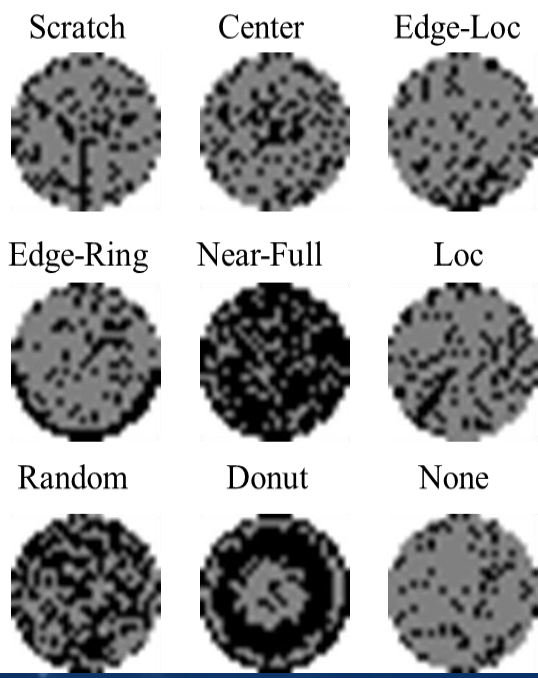
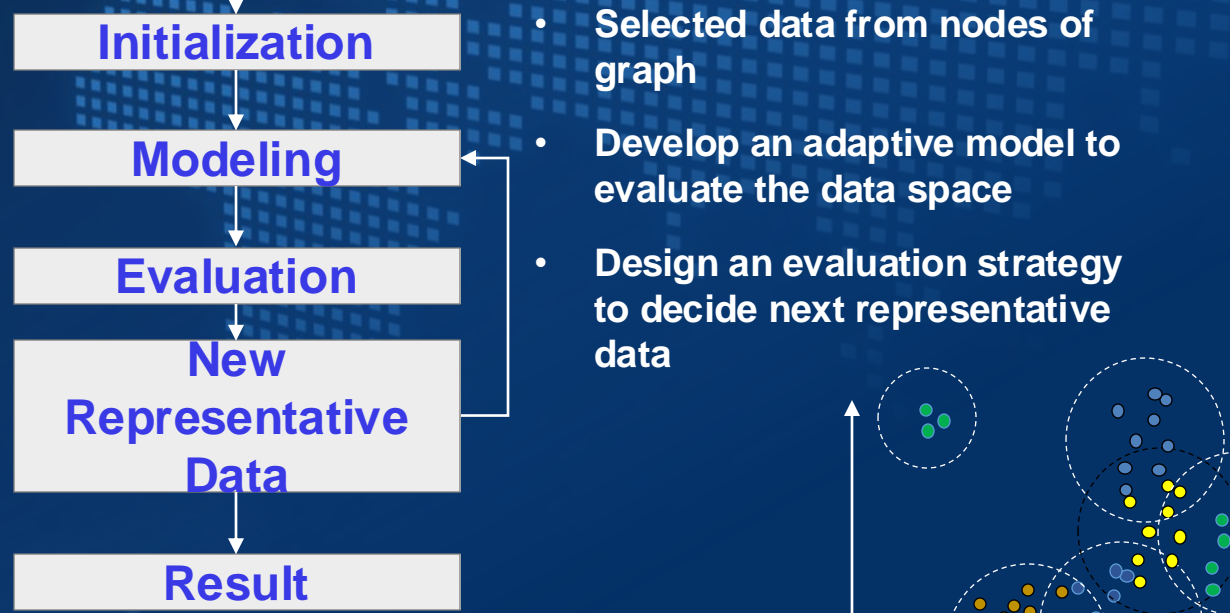


Example: Data Representation using Topological Data Analysis (TDA)

TSMC WM-118K Dataset (810,000)



Constructed by only labeled data (170,000)
Node color is represented by mixture proportion of each class



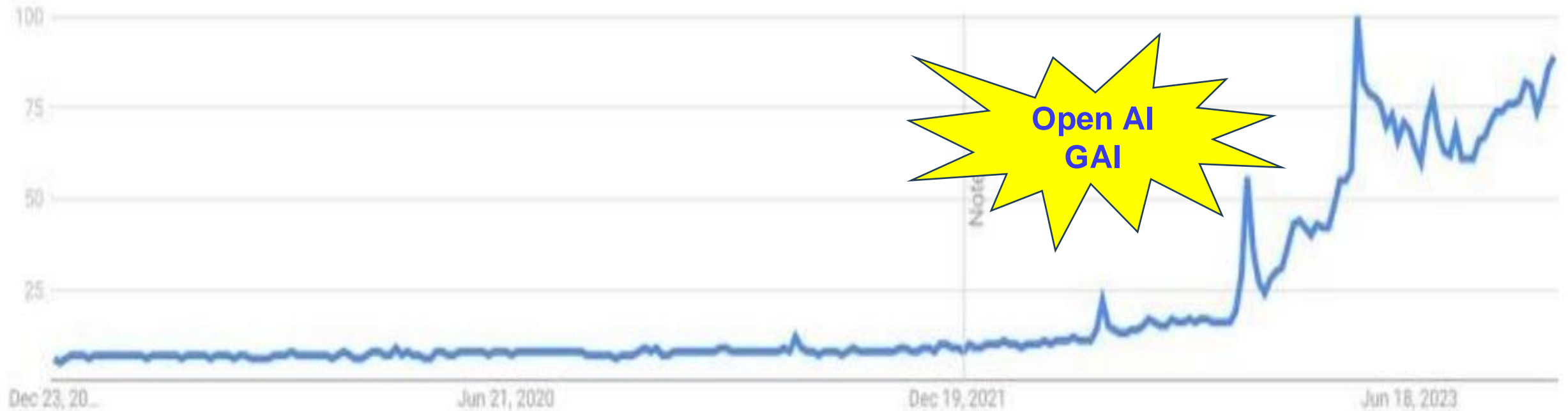
Ref: https://en.wikipedia.org/wiki/Wafer_testing#/media/File:Wafer_prober_service_configuration.jpg

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1. Trends of Data Centric Systems and Unmet Needs
- 2. Trends of AI, Industrial AI Systems**
3. Some Examples in Semiconductor Manufacturing
4. Training of New Breed of Industrial AI Engineers

AI Has Been Gaining Amazing Attention since 2022

Level of Attention



\$16.7 B

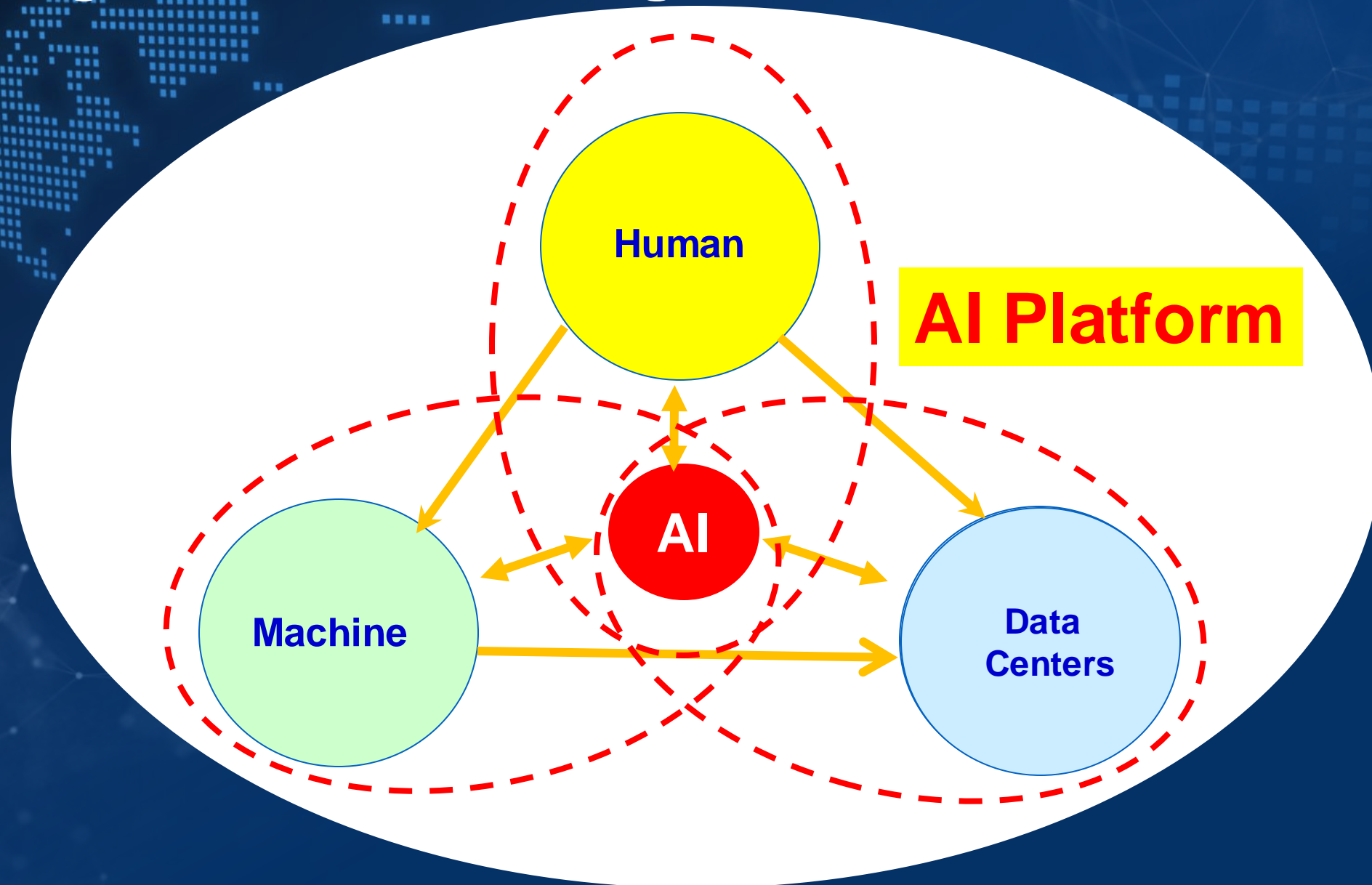
NVIDIA Revenue

\$26.9 B

NVIDIA Valuation >\$ 3T

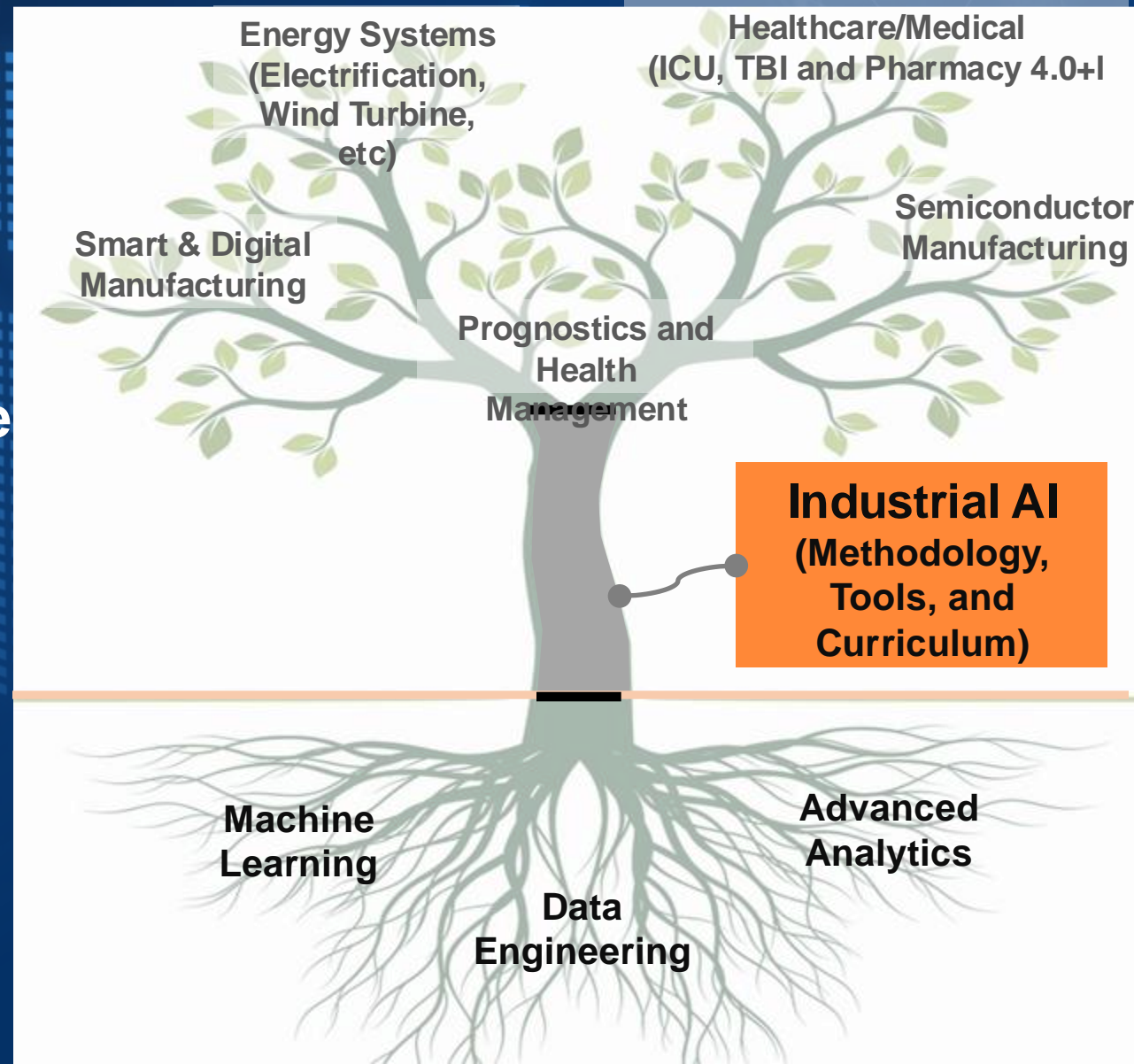
\$50 B

Evolving Role of AI from Algorithm to Platform, and to Agent



Industrial AI

► **Industrial AI** is a *systematic discipline* which focuses on developing, validating and deploying various machine learning algorithms *systemically and rapidly* for industrial applications with *sustainable performance*.



Domain




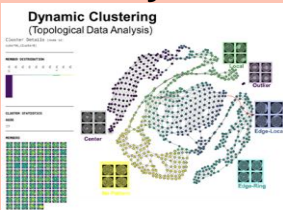
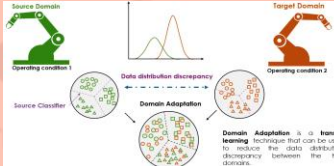
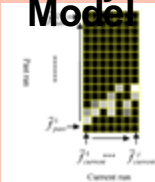
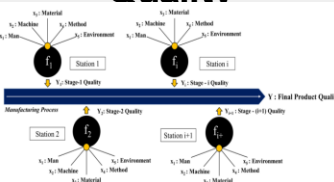
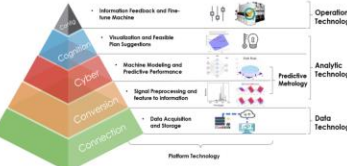
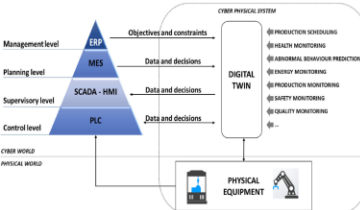
+

Discipline

+

Data

Overview of Industrial AI Systems

Industrial AI	Target Systems	Traditional Machine Learning	Non-Traditional Machine Learning	Methodology Platform
<ol style="list-style-type: none"> Manufacturing AI <ul style="list-style-type: none"> Semiconductor Machine Tools Industrial Robots Production Quality New Energy AI <ul style="list-style-type: none"> Wind Turbine Power Supplies EV Battery Oil & Gas Transportation AI <ul style="list-style-type: none"> Automotive High-speed Trains Aviation Marine Vessels Healthcare AI <ul style="list-style-type: none"> Rehabilitation Neurocritical Care Sports Medicine Chronic Care 	<ol style="list-style-type: none"> Component  Unit  Fleet  	<ol style="list-style-type: none"> Signal Process & Feature Extraction Physics-Based Model Data-Driven Model Deep Learning Health Assessment Health Diagnosis Predictive Maintenance Remaining Useful Life Failure Modes and Effects Analysis 	<ol style="list-style-type: none"> Topological Data Analysis  Domain Adaptation & Transfer Learning  Similarity-Based Model  Surrogate Model Just-in-time Model Industrial Large Knowledge Model 	<ol style="list-style-type: none"> Stream-of-Quality  5C-level Cyber-Physical System  Digital Twin 

Traditional Machine Learning vs. Non-Traditional Machine Learning

AI

**Traditional
Machine Learning**

Supervised Learning,
Unsupervised Learning,
Reinforcement Learning,
Federated Learning,

Non-Traditional Machine Learning

Transfer Learning, Domain Adaptation,
Similarity-based Learning,
Stream-based (SoX) Learning,
Industrial Large
Knowledge Model, etc.

Traditional Machine Learning Methods and Algorithms for Industrial Systems

Machine Learning Methods

Algorithms

Fault Detection

Fault Diagnosis

Health Assessment

Remaining Useful Life Prediction

One-Class Detection	Control Charts (Statistical Process Control)	One-Class Support Vector Machine	PCA - T^2	SOM-MQE	GMM-L2
Binary Classification	Naïve Bayes	Logistic Regression	Decision Trees	Support Vector Machine	
Binary/ Multi-class Classification	(Deep) Neural Networks	Fuzzy Inference Systems	Self-Organizing Map		
Supervised Regression	Linear Regression	General Linear Regression	Gaussian Process Regression	(Deep) Neural Networks	
Unsupervised Regression	Parametric Method	Hidden Markov Model	Kalman Filters / Particle Filters	Factor Analysis	Principal Component Analysis
Supervised Prediction	Linear Regression	General Linear Regression	Gaussian Process Regression	(Deep) Neural Networks	
Unsupervised Prediction	Kalman Filters / Particle Filters	Stochastic Process Model	Similarity Based Model	Survival / Hazard Analysis (Cox Model)	

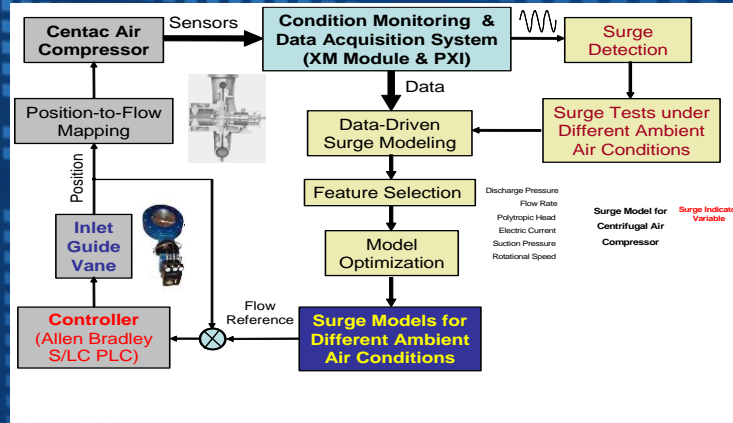


Zero Downtime Compressor at Toyota Georgetown, KY

AI for Compressor Surge Prediction



PCA + SVM



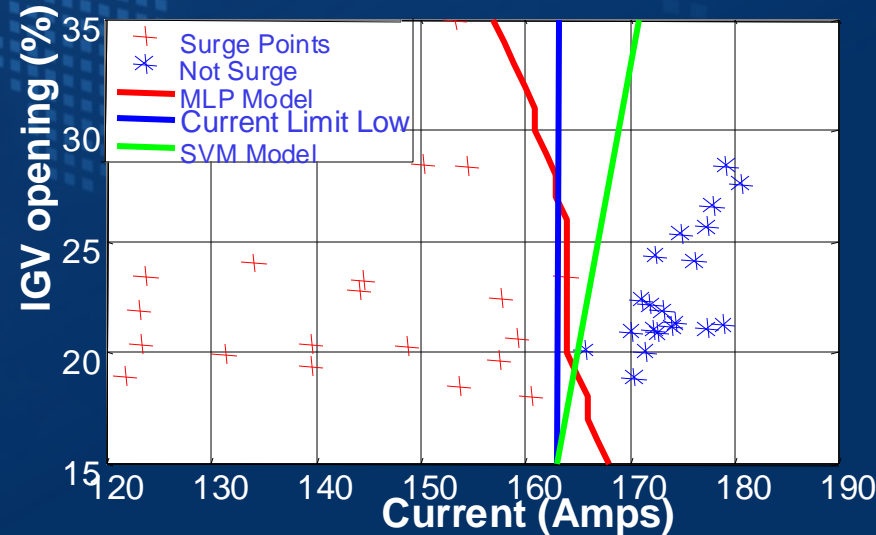
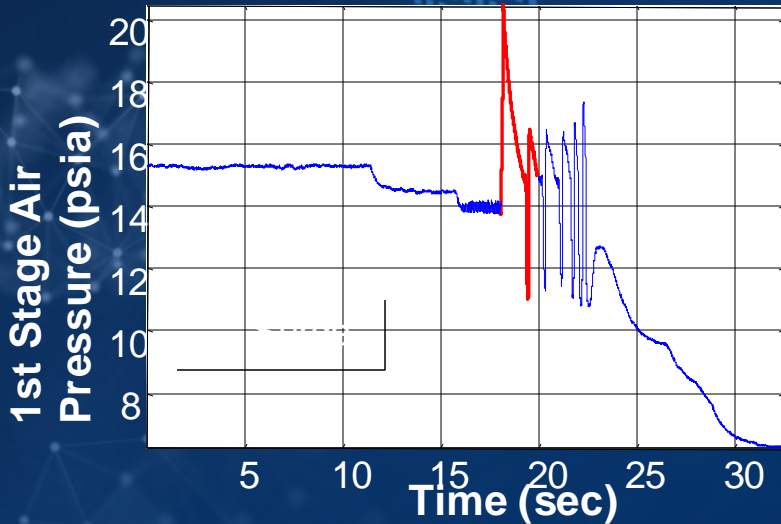
Go for zero-downtime performance by 'testing the machine's blood'

September 29, 2021

By Ilene Wolff
Contributing Editor,
SME Media

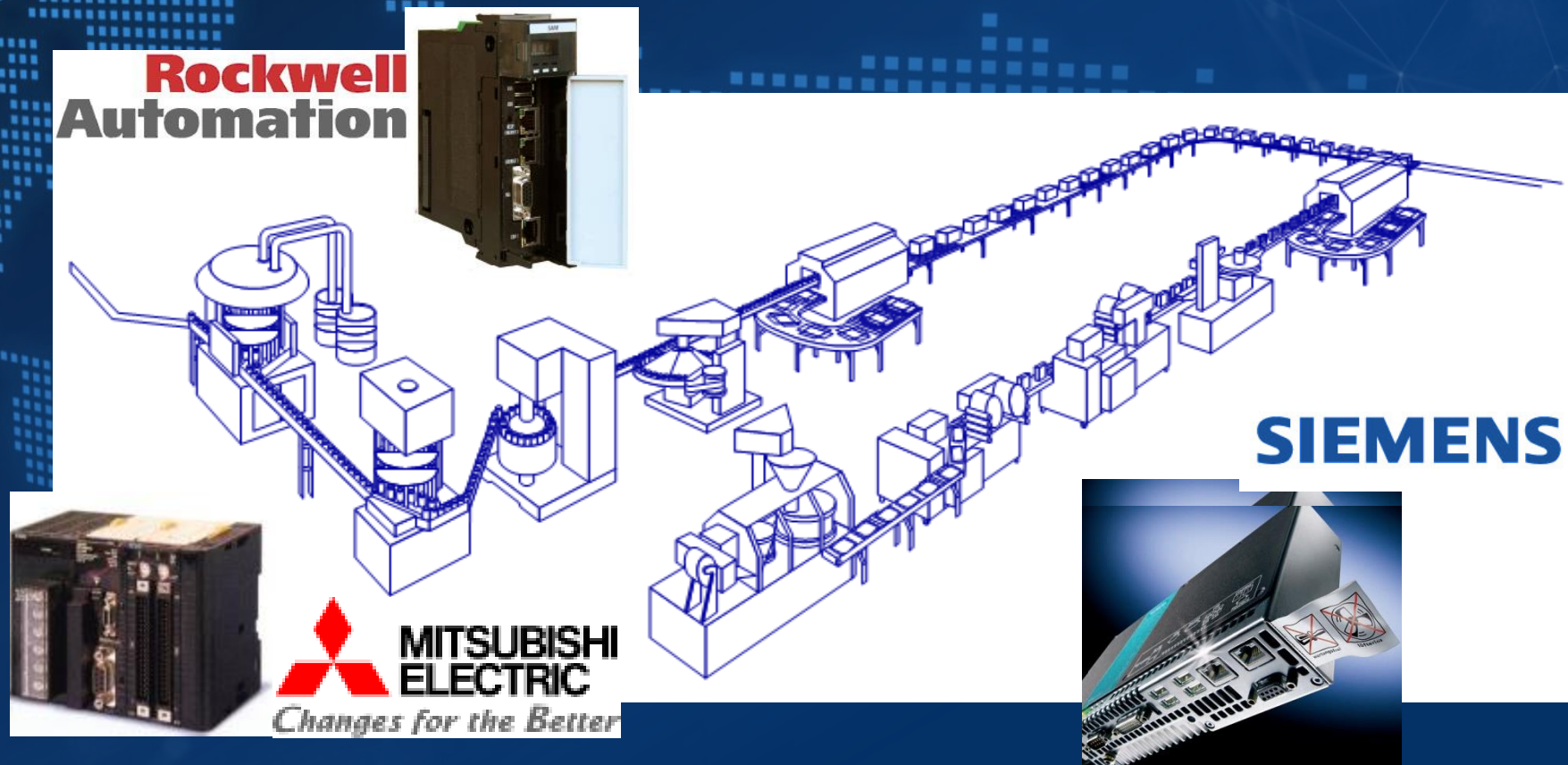
In the mid-2000s, the compressed air system at the Toyota North America plant in Georgetown, KY, crashed on average more than once a year. That led some at the plant to wonder whether leveraging machine learning and AI could address this problem by providing anomaly detection, fault identification and, most importantly, prediction of impending failures before they occur.

Unplanned downtime of the compressed air system meant, of course, that the entire factory had a problem. The paint shop used compressed air for...



**Zero Downtime
No failure
since 2006**

Embedded AI for Production Systems



Reconfigurable AI Augmented PLC Systems

Enable Zero-Breakdown Productivity

AI-Augmented Uptime Improvement for P&G (2007-11)

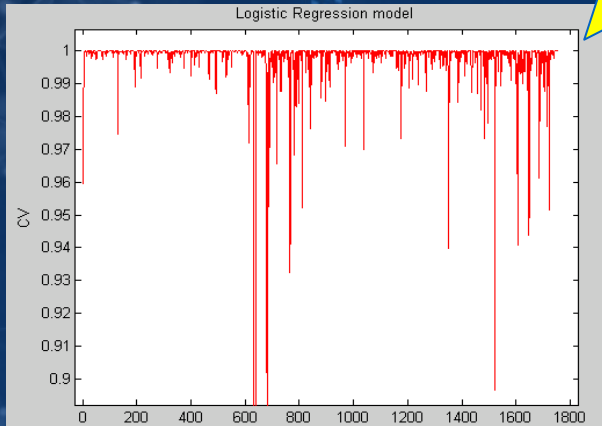


2012 NSF I/UCRC
Economic Impact Report

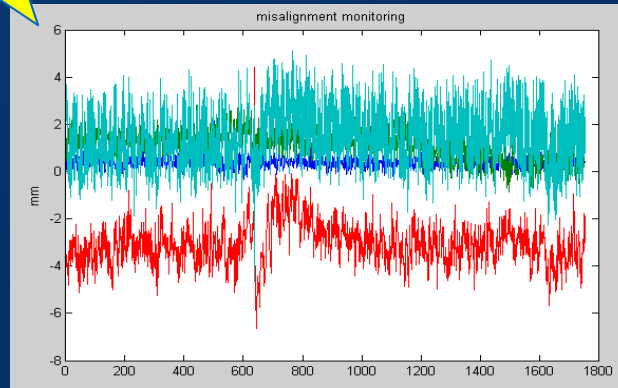
**\$450 M
Saving/Year**

DM1

web 1
web 2



Real-Time Performance



Process Quality Monitoring



AI Augmented Machine Tool Health Monitoring Technology Demonstrated in 2018 and Commercialized Today

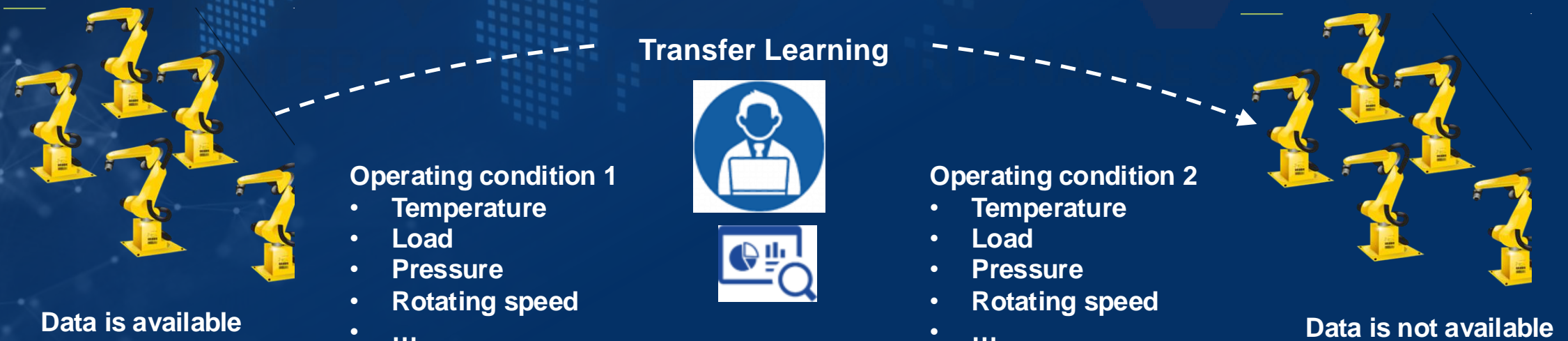
Mazak



**Mazak
Discovery Week
Oct. 2023**

Non-Traditional Machine Learning— Transfer Learning

- » The most optimum way of learning is to utilize the pre-acquired knowledge as the basis of intended learning plan.
- » In machine learning application, the exchanging knowledge across different tasks is named as transfer learning.
- » In industrial applications, providing the data under different operating and health conditions is not straightforward.



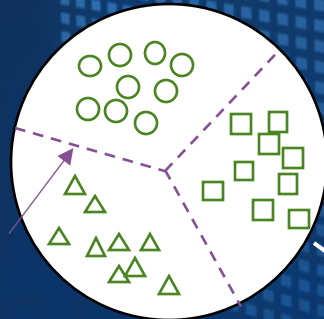
Domain Adaptation

Source Domain



Operating condition 1

Source Classifier



Data distribution discrepancy

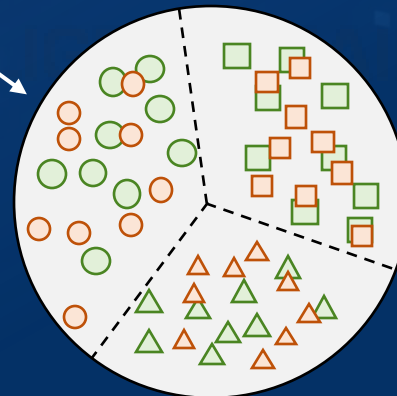
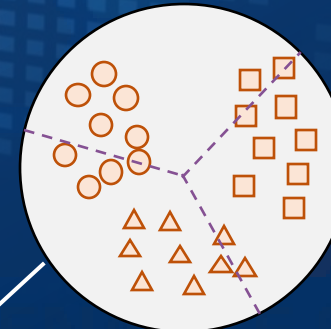


Target Domain



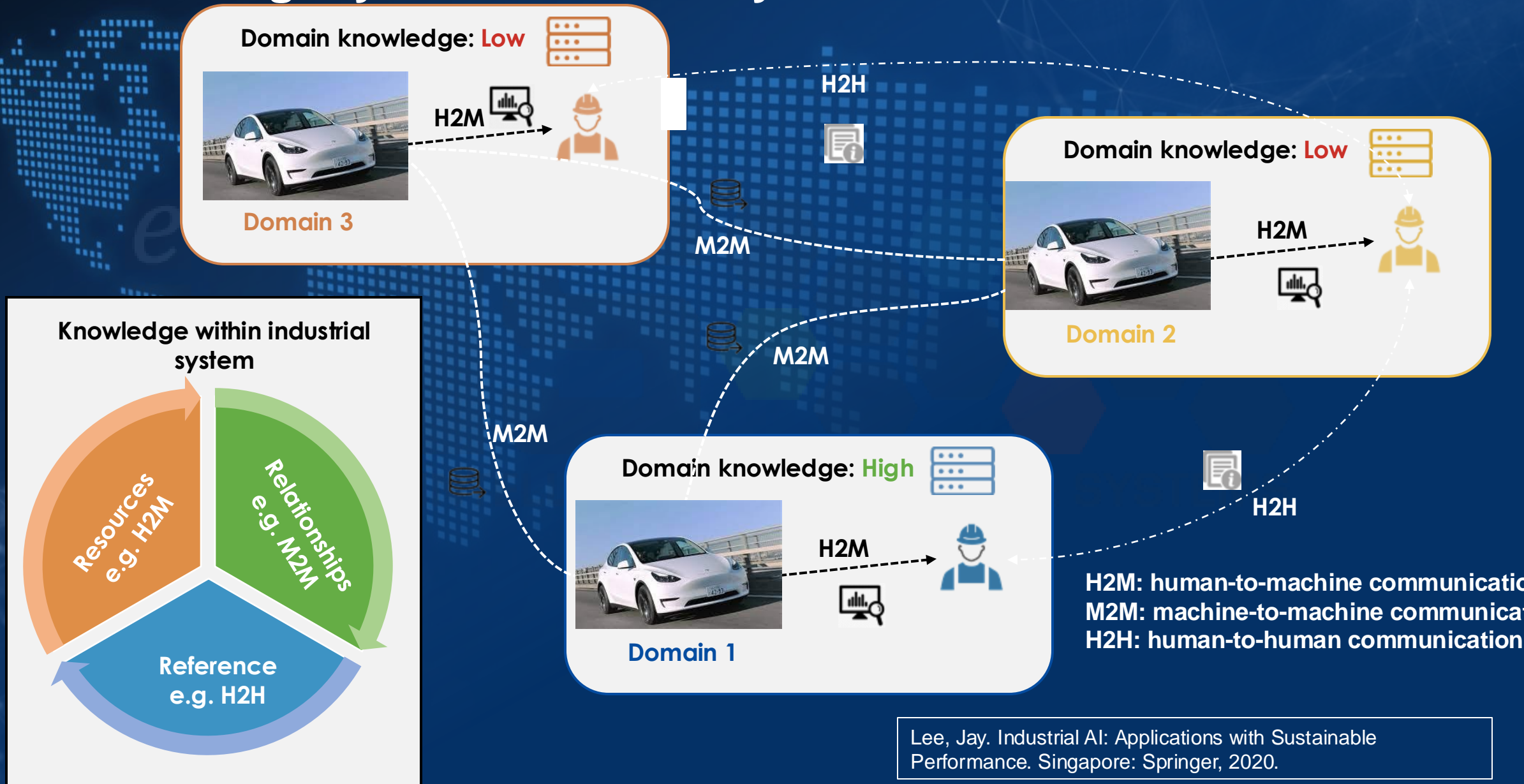
Operating condition 2

Domain Adaptation



Domain Adaptation is a transfer learning technique that can be used to reduce the data distribution discrepancy between the two domains.

Integrated Machine Learning for Highly Connected Systems



Tesla Full Self-Driving (FSD) Beta V12 (released on 8/26/2023)



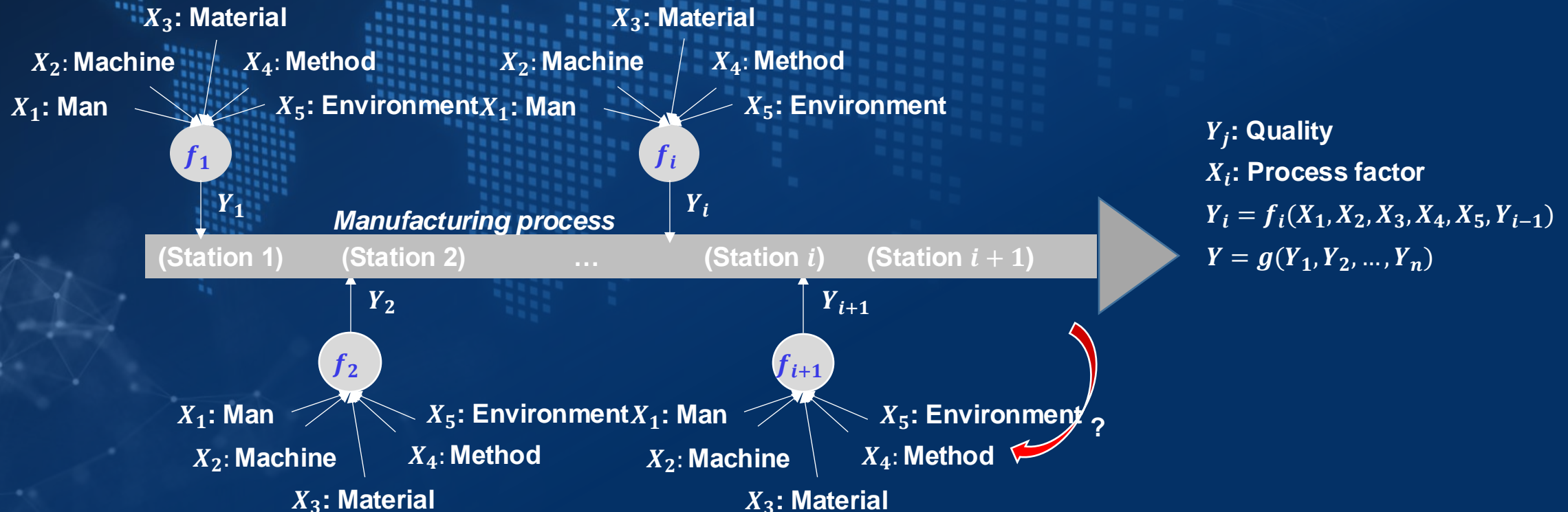
- Musk highlighted that FSD V12 relies entirely on artificial intelligence and neural networks to drive, with no traditional code. He stated “there are no heuristics, no lines of code” to explicitly tell the car how to handle situations like traffic lights or turns. Instead, the system has been trained on large volumes of driving footage to learn proper driving behavior.
- Reduced 90% of the code with better performance.

Non-Traditional Machine Learning

Stream-of-X (SoX) Methodology

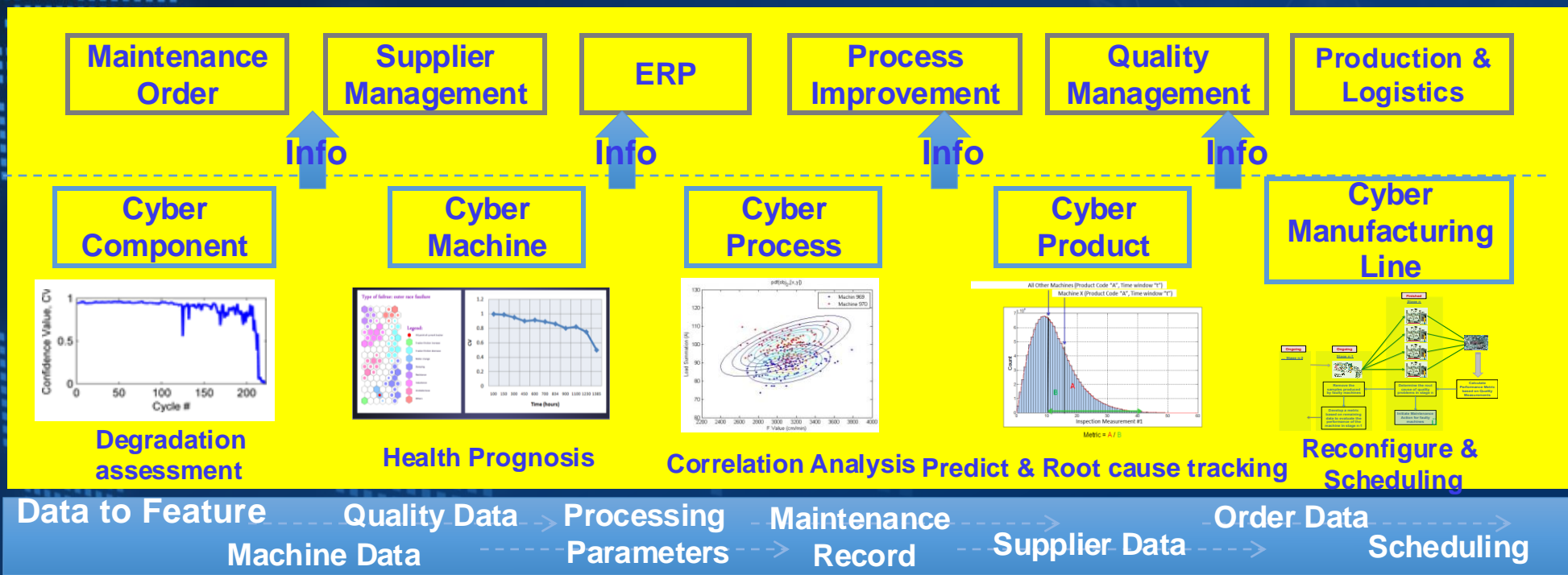
Stream of Quality™ (SoQ™) is a traceable systematic methodology for connected quality.

- It can collect the manufacturing information of a product during its production processes.
- The data of each station can be labeled with a time stamp and saved in an immutable block. Then the product quality data forms an information stream and can be stored in structured block chain.
- It can be used to describe the product, trace the entire production process and analyze the root cause of quality issues.

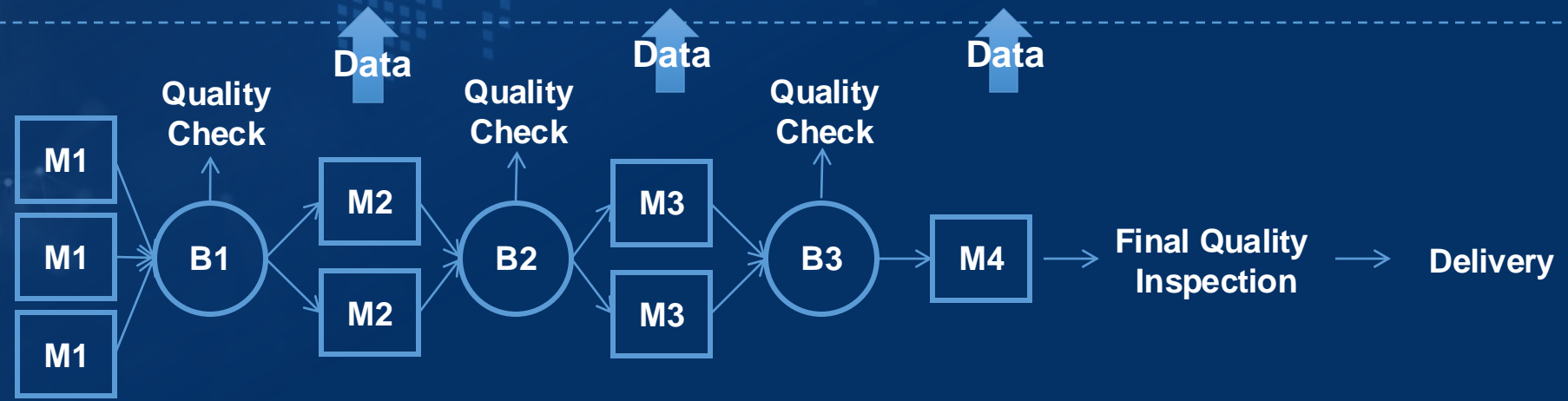


Digital Twin of Manufacturing Systems

Data Centric Manufacturing Systems



Physical Manufacturing Systems



Foxconn World Economic Forum (WEF) Lighthouse Factory Award



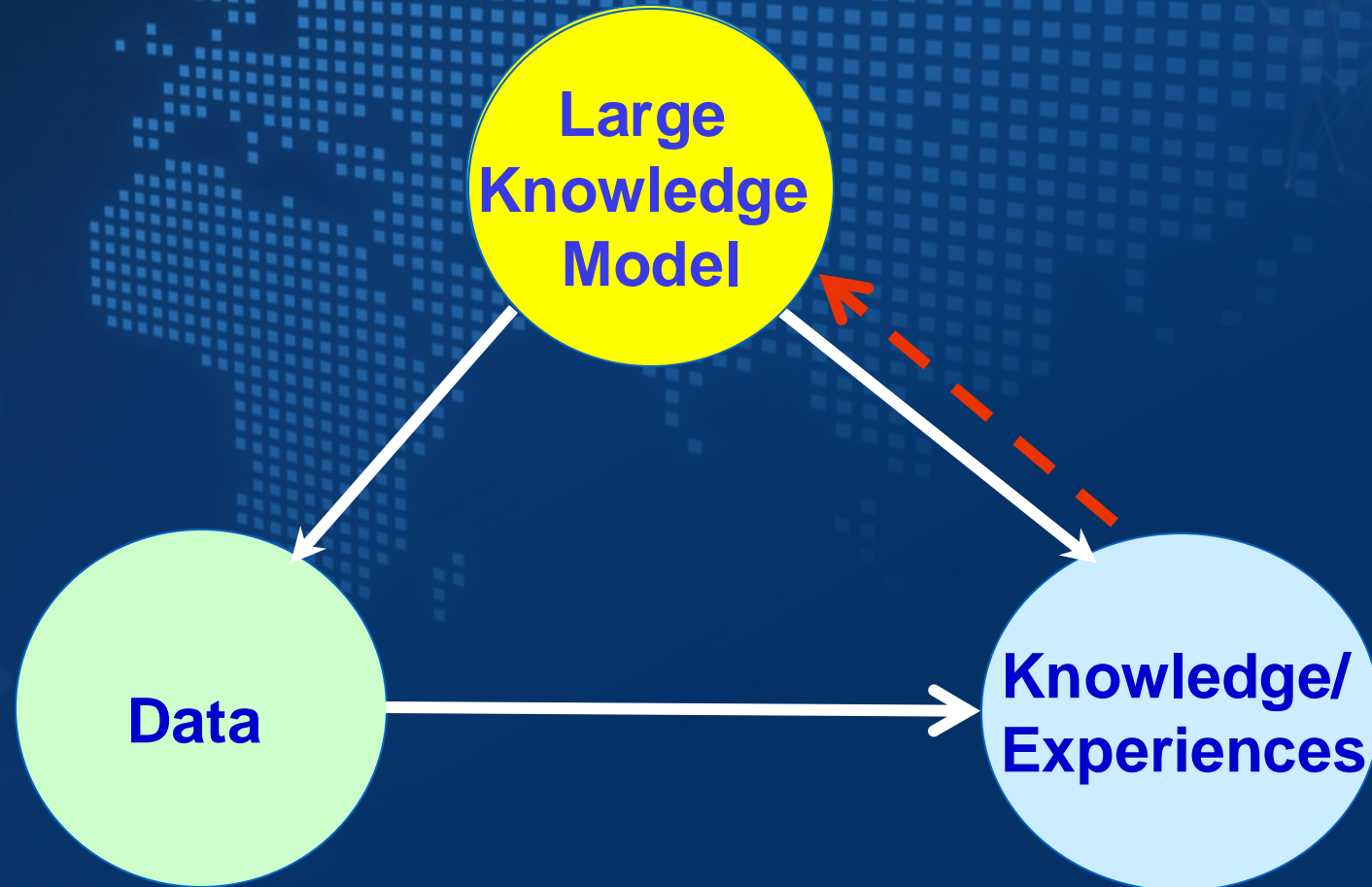
Efficiency  30%

Inventory  15%

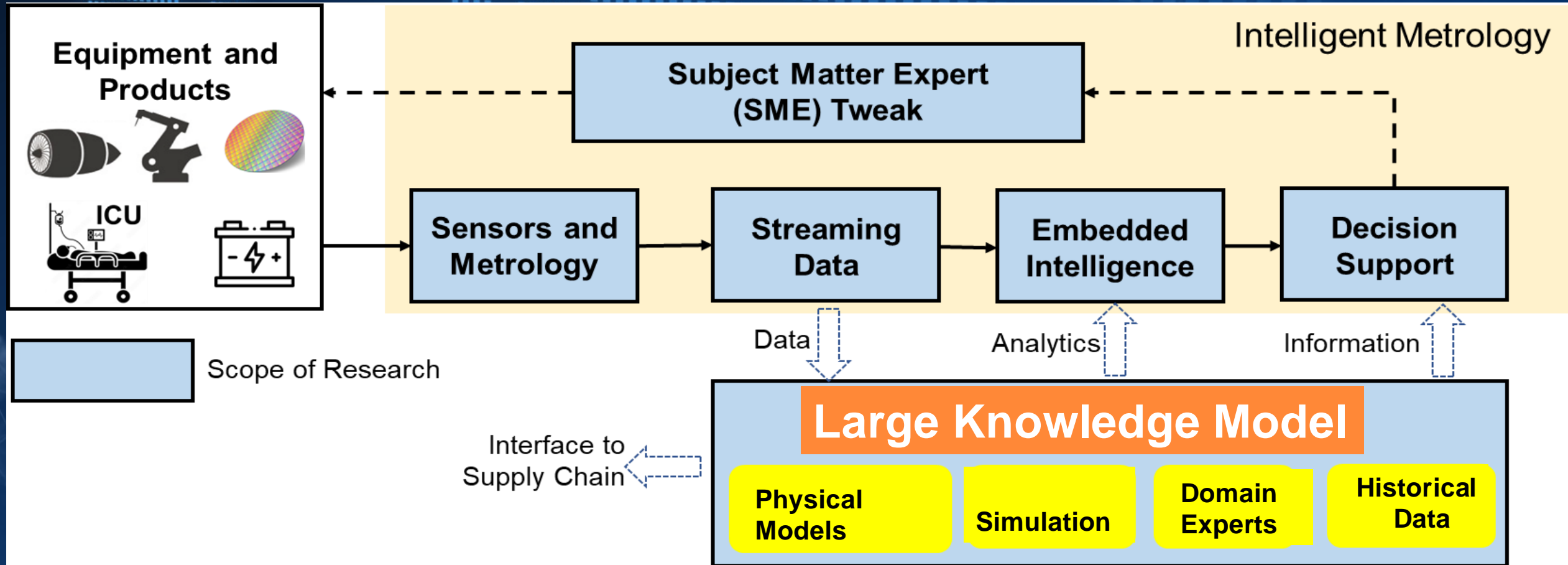
Labor  92%

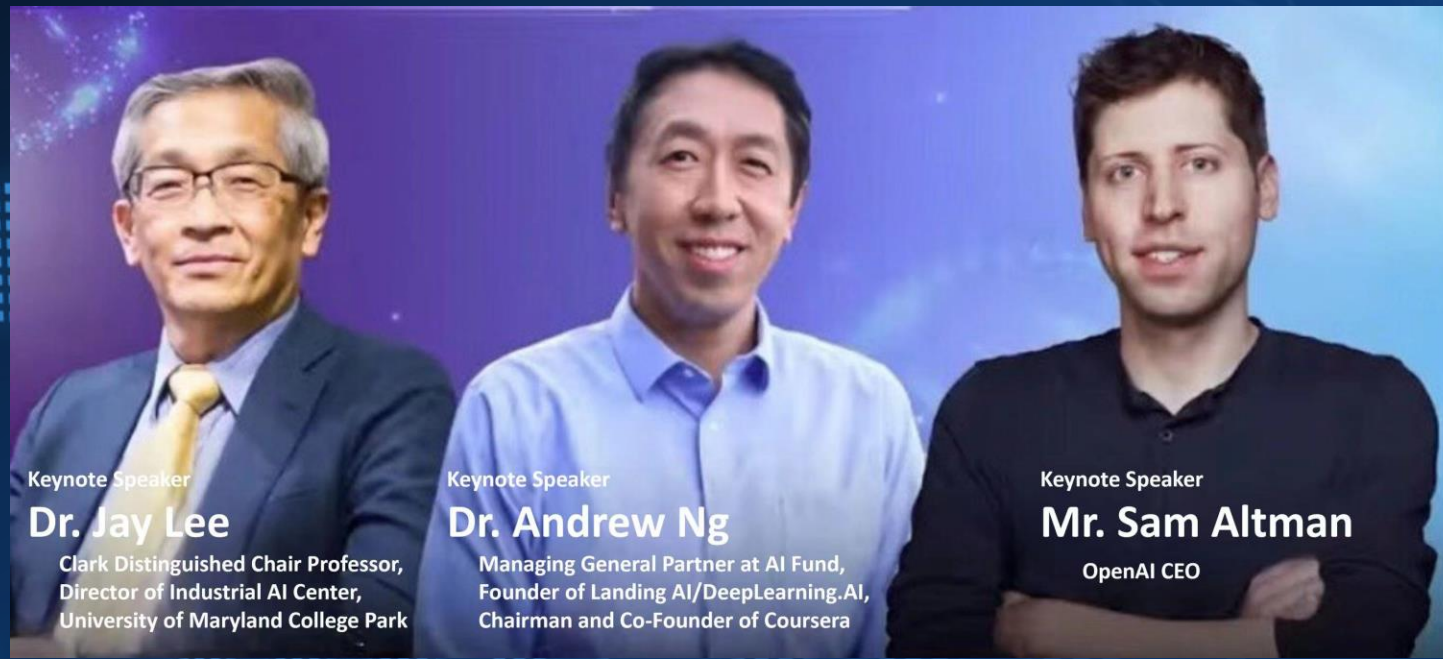
Lights Out Factory

Domain, Data, and Large Knowledge Model

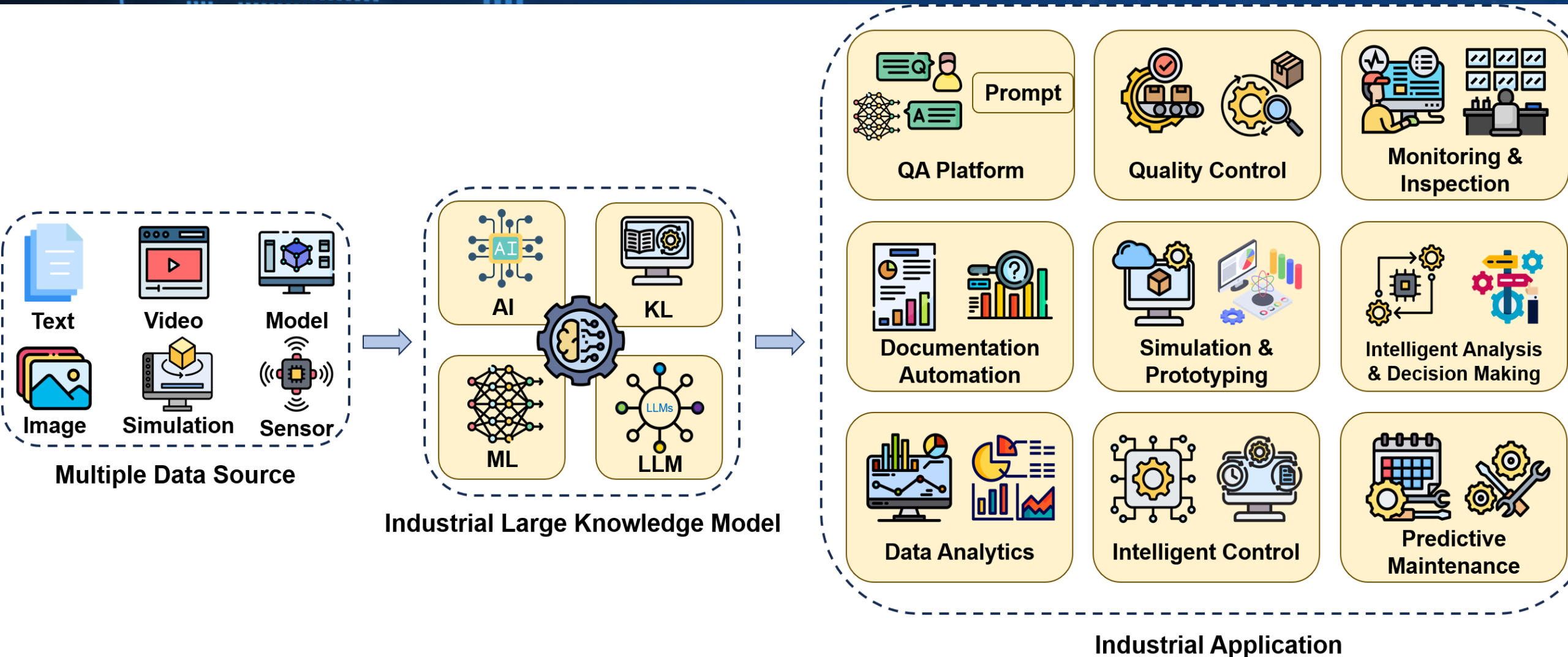


Industrial Large Knowledge Model for Data-Rich Complex Industrial Systems





Industrial Generative AI (IGAI) – Industrial Large (Domain) Knowledge Model



Large Language Models (LLMs) vs. Large Knowledge Models (LKMs)

- **Large Language Model (LLMs):**

LLMs like ChatGPT, are trained on vast datasets of text. They excel in understanding and generating human language, making them adept at tasks like natural language processing, conversation, and text generation. However, their knowledge is often general and not specialized.

- **Large Knowledge Model (LKMs):**

LKMs are designed to process and understand large volumes of domain-specific knowledge (May have different types of data, especially machine sensor data). They are tailored for specific industries or applications, incorporating detailed, expert-level understanding of particular fields.

LLMs vs. LKMs in Industrial AI

LLMs

LKMs

Data Handling and Privacy

Potential concerns with data security, as they often require sending data to third-party servers (Like OpenAI) for processing

Offer greater control over data privacy, as they can be hosted within a company's secure environment

Domain-Specific Knowledge

Knowledge is general may lack deep, industry-specific insights

Specialized provide in-depth, technical knowledge relevant to specific industries

Integration and Customization

Need additional resources for integration and customization to fit specific industrial requirements

Easily tailored and integrated into existing systems, aligning closely with industry-specific needs

Scalability and Maintenance

Highly scalable but necessitates external updates and maintenance

Scalability and updates are managed internally, offering more control by the company but requiring dedicated resources

Real-Time Decision Making

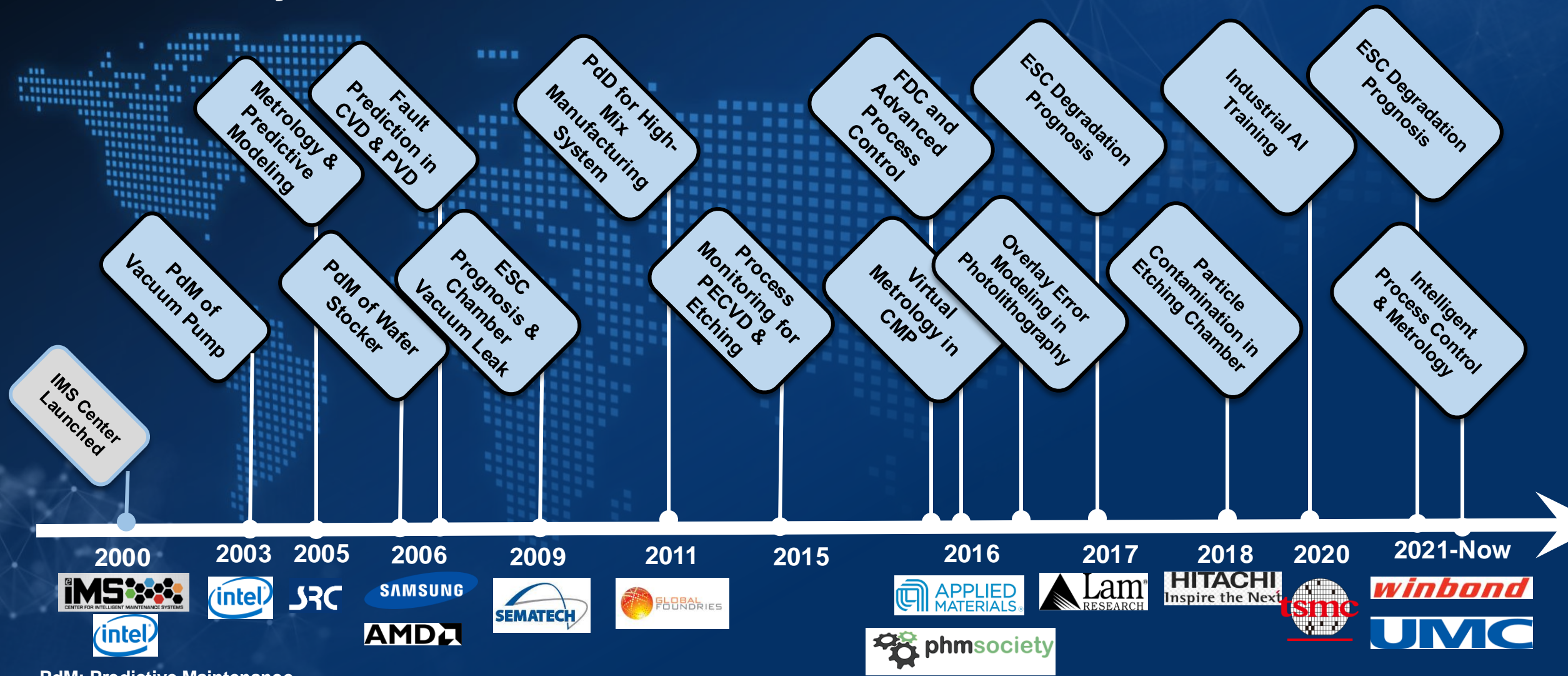
Limited in handling real-time, complex industrial decisions due to their generic training

Better suited for real-time decision-making in industrial settings, leveraging specific industry data

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History of Our Semiconductor Research



PdM: Predictive Maintenance
 ESC: Electrostatic Chuck
 PECVD: Plasma Enhanced Chemical Vapor Deposition
 CMP: Chemical Mechanical Polishing
 FDC: Fault Detection & Classification
 PVD: Physical Vapor Deposition

Chamber Difference Quantification using Traditional PCA

Goal:

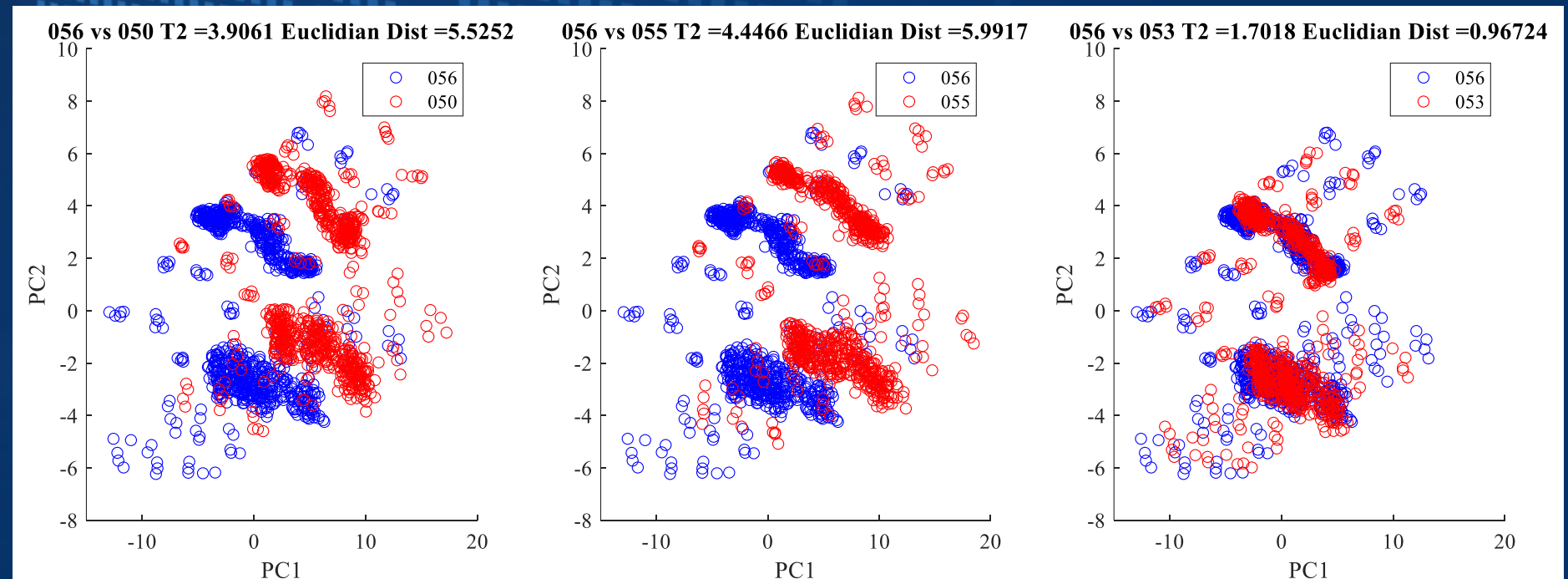
To compare the difference and measure the distance between different machines based on the machine fingerprints (the PCs of IE features under different machine offset settings or DG configurations).

Steps:

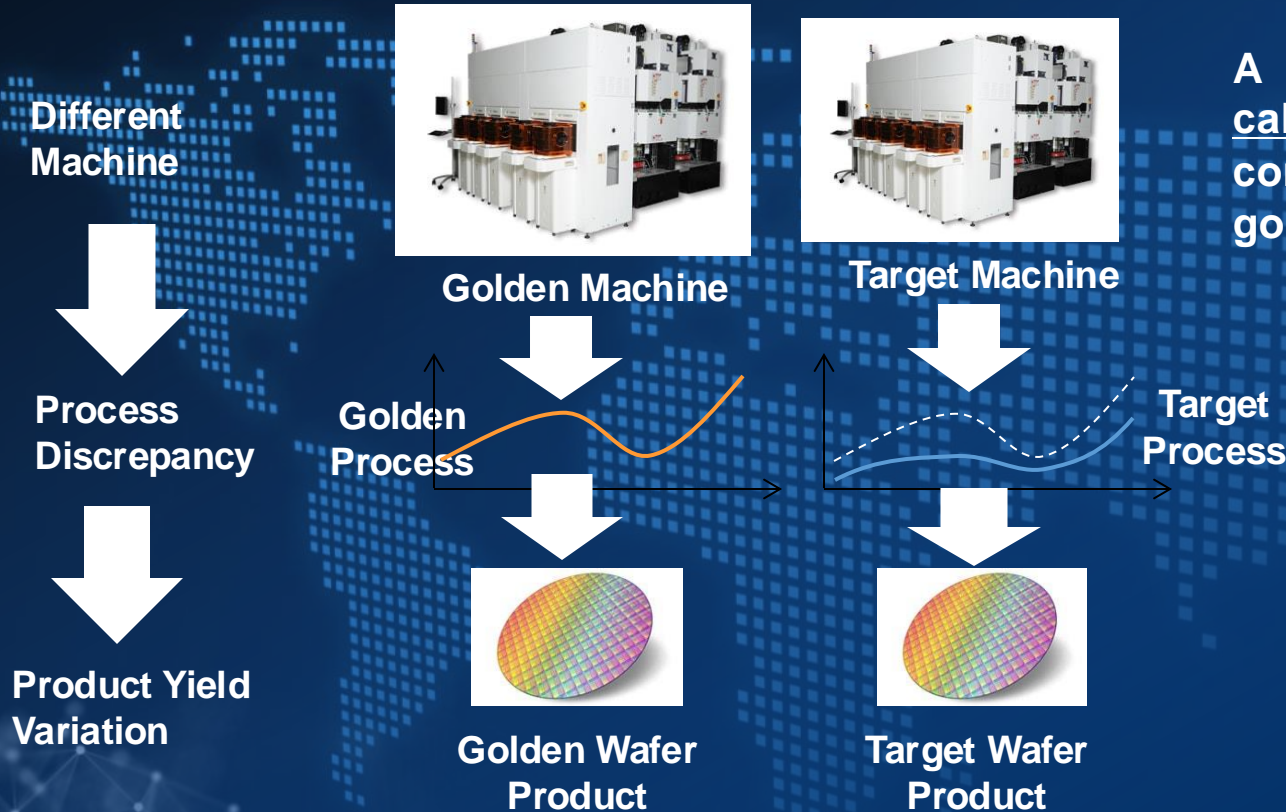
1. Extract statistic features of sensors
2. Conduct sensitivity analysis and select features
3. Perform PCA on selected feature matrix of all 870 experiments (first 5 PCs are selected)
4. Calculate averaged T^2 and Euclidian distance as discrepancy measurement
5. Visualize PC of different machines

Result:

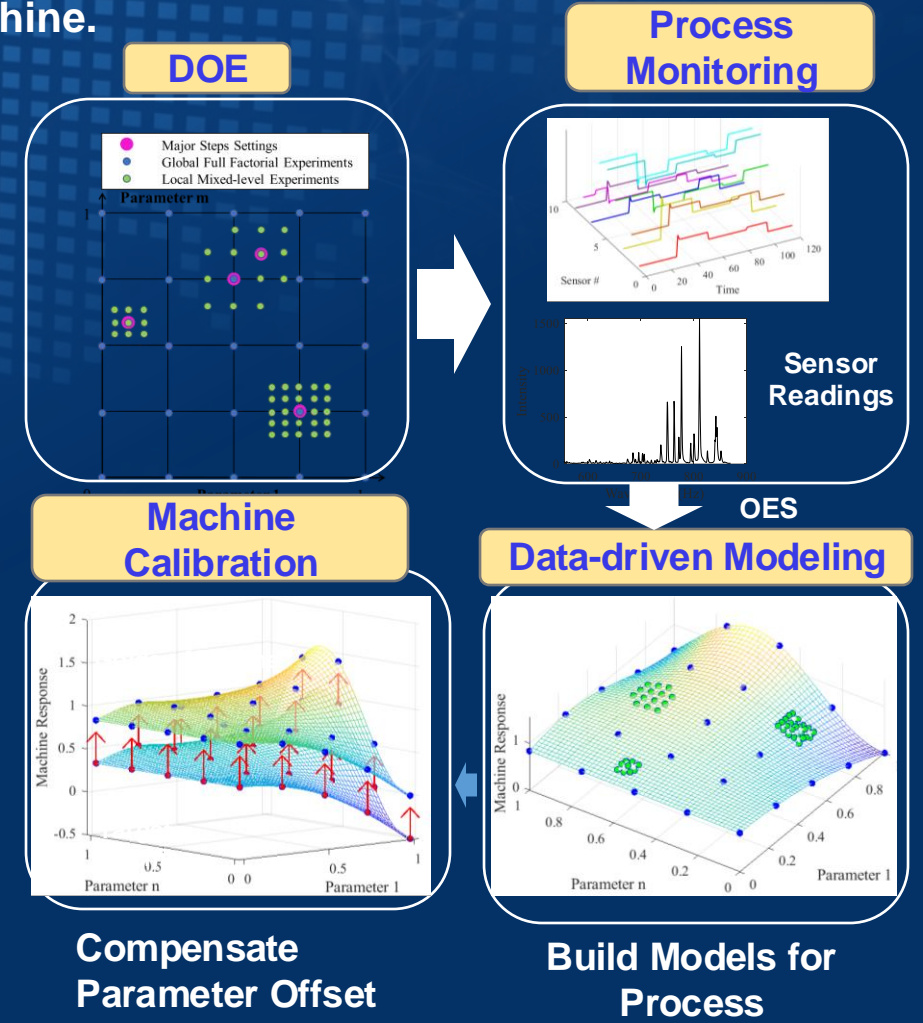
Machine 1 (056) is compared with 2 (055), 3 (055), and 4 (053)



Data Centric Metrology for Semiconductor Manufacturing



A systematic process-data-driven approach which caliberates the target machine input parameters to compensate machine responses discrepancy from the golden machine.



Compensate Parameter Offset

Build Models for Process

- Chamber matching is the common practice to increase production consistency and yield by controlling the machine process based on feedback from product metrology.
- Machine calibration is the common practice to adjust machines to have identical performance by assigning global offsets on machine settings.
- Chamber matching and machine calibration could significantly improve production yield of the etching process.

Current NIST Award

Digital Twin - Enabled Yield Enhancement Methodology for Semiconductor Manufacturing by Using Stream-of-Quality Analytics

Overall Objectives: This proposal aims to model the complex process-to-process (i.e., CMP-Litho-Etch) interaction and investigate its impact on product yield (i.e., uniformity, CD, e-test) by developing novel SoQ analytics. The established SoQ will be further utilized to perform root-cause analysis and inter-process control for yield enhancement.

	AMAT	UC & UMD
Research Tasks	<ul style="list-style-type: none"> • Simulation/Production/Yield Data • Fab-Wide Digital Twin Integration Framework Design • Semiconductor Domain Experts 	<ul style="list-style-type: none"> • Stream of Quality (SoQ) Analytics • SoQ Based Root Cause Analysis • Model validation and enhancement

Expected Deliverables:

- 1) Novel SoQ analytics that can model complex process-to-process interaction in semiconductor manufacturing
- 2) Root Cause Identification based on the SoQ analytics
- 3) Knowledge graph (data-driven ontology) for root-cause analysis (Optional)
- 4) Novel digital twin framework design for fab-wide VM model integration and management
- 5) New public data for the entire research community

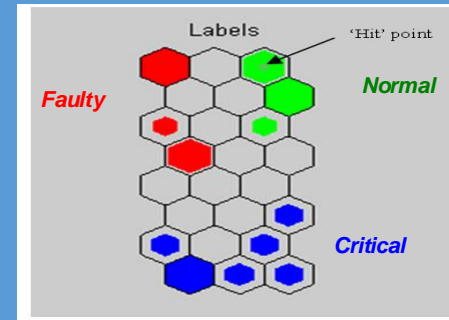
Prognostics and Health Management for Commercial Jet Engine Fleet



Feature Extraction and Signal Processing

Detect variations and jumps in parameters such as Exhaust Gas Temperature (EGT), spool rotational speed, pressure, etc.

Health Assessment using Self Organizing Map (SOM)

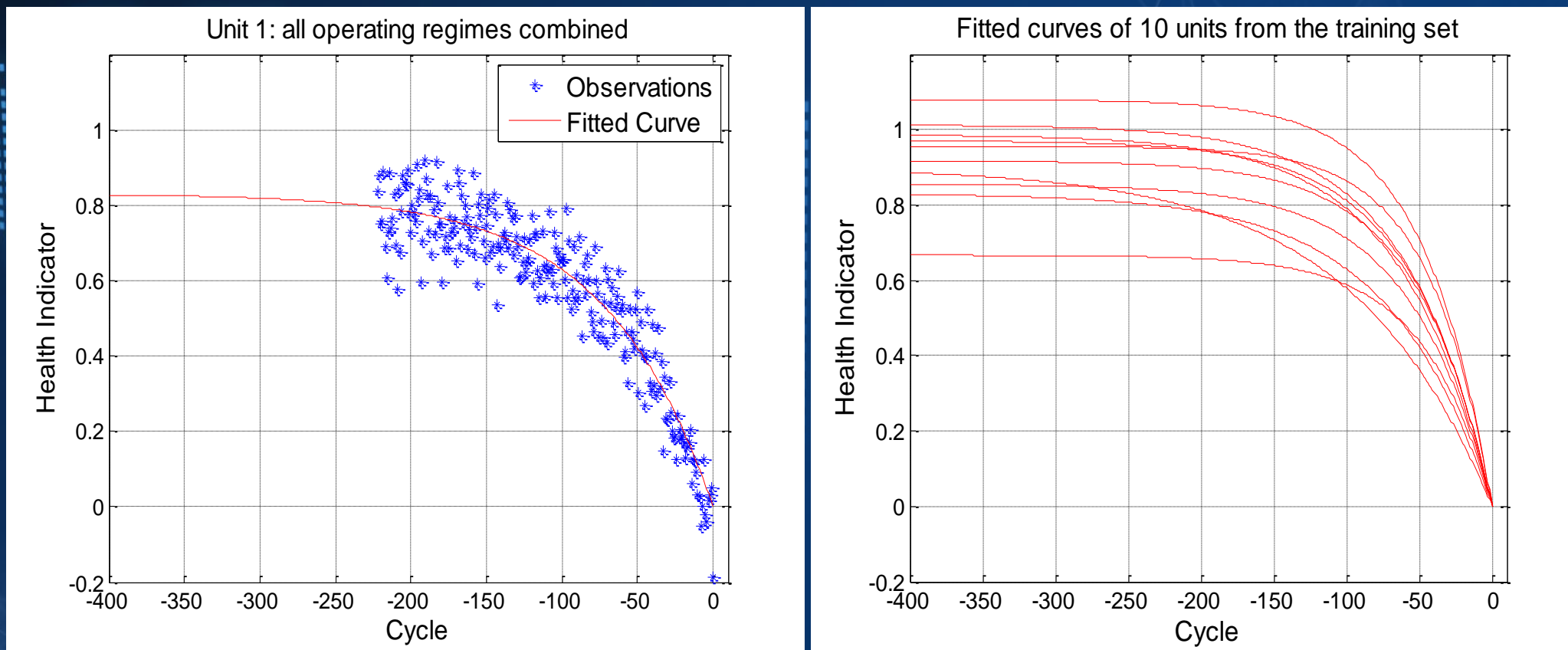


Phase I Deliverables

- Improved anomaly detection
- Precision classification of anomalies
- Earlier fault prediction

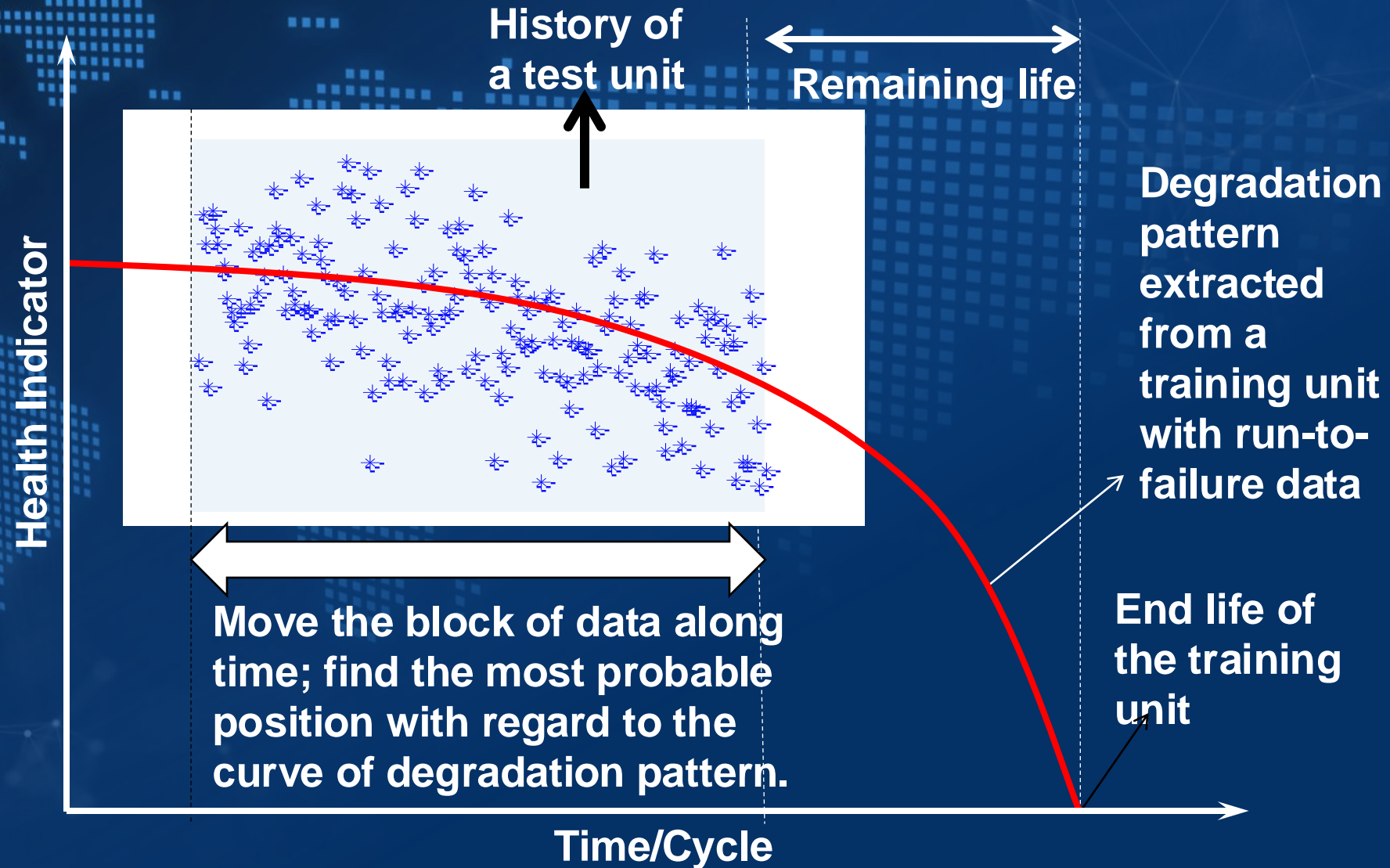
Value

Deliver Competitive Value to Airlines and Customers

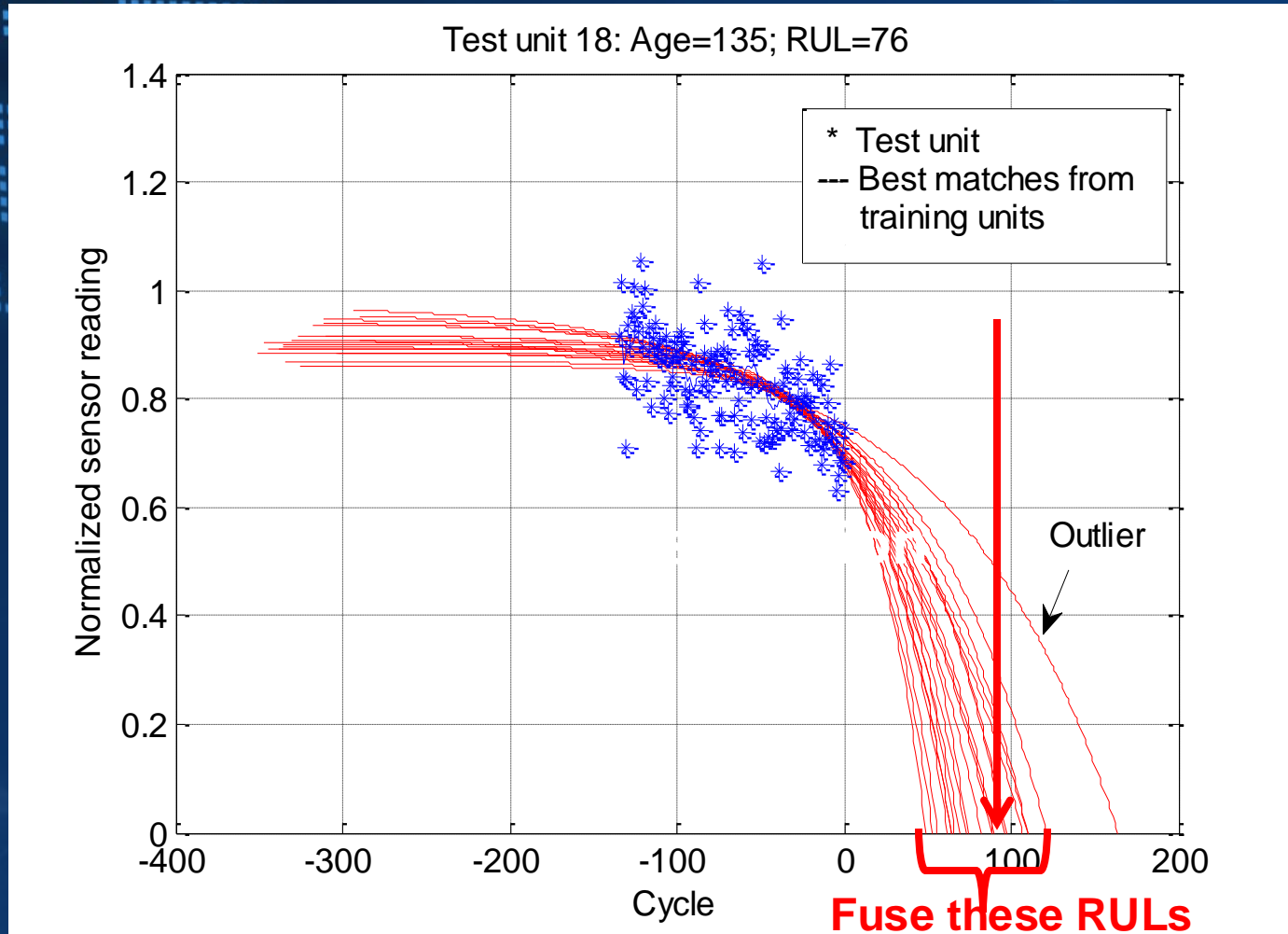


- Fit an exponential degradation curve for each training unit
- Create a library of degradation patterns/models

Similarity Methodology (Fleet-Based System)



Remaining Useful Life (RUL) Fusion



Candidates: Rank by distance score; cut at 25% increase of the smallest score

Remove outliers

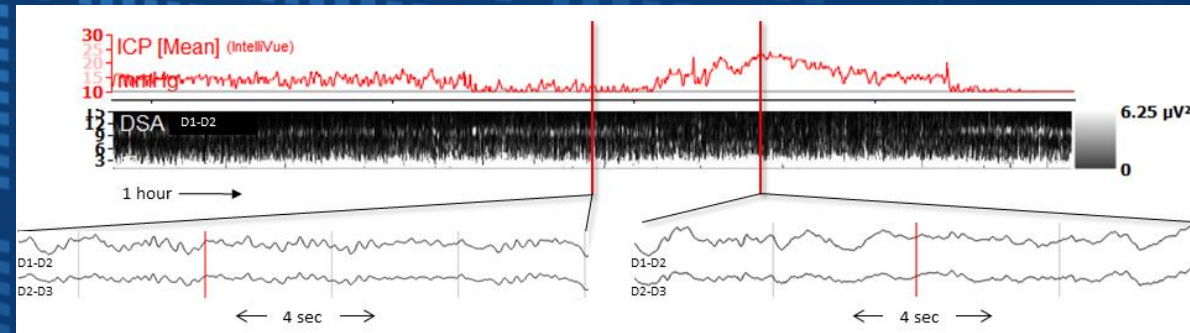
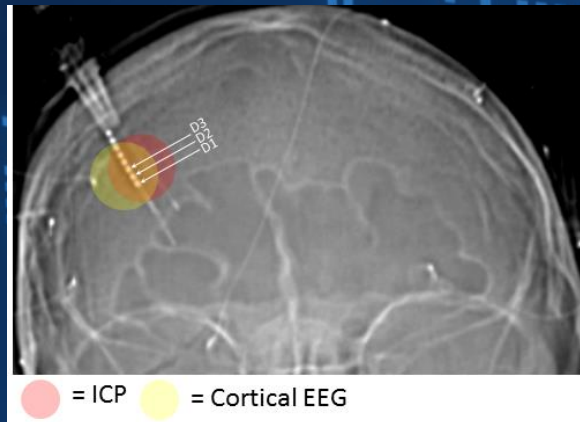


AI-Augmented Analytics for ICU

Traumatic Brain Injury (TBI)

Objectives: To determine whether ICP elevations are associated with the presence of ischemic changes in the Electroencephalography (EEG) recorded at the cortex and on the scalp

Dataset: 104 (Traumatic Brain Injury)TBI patients with ICP and EEG waveform data in unsynchronized 120Hz(ICP) and 256Hz(EEG)



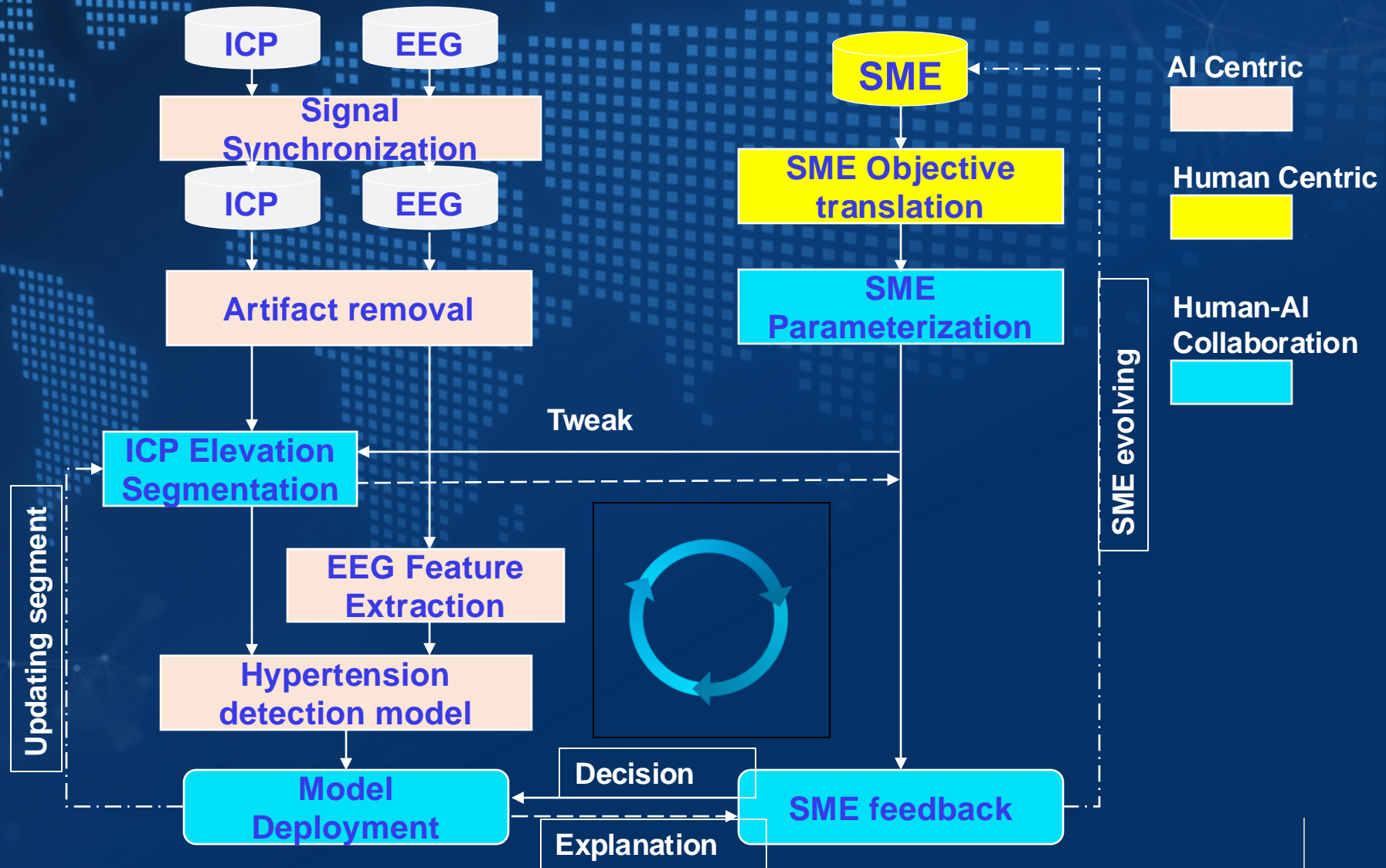
Mixture of delta and high theta frequencies are seen

attenuation of the faster frequencies and enhanced higher amplitude delta frequency

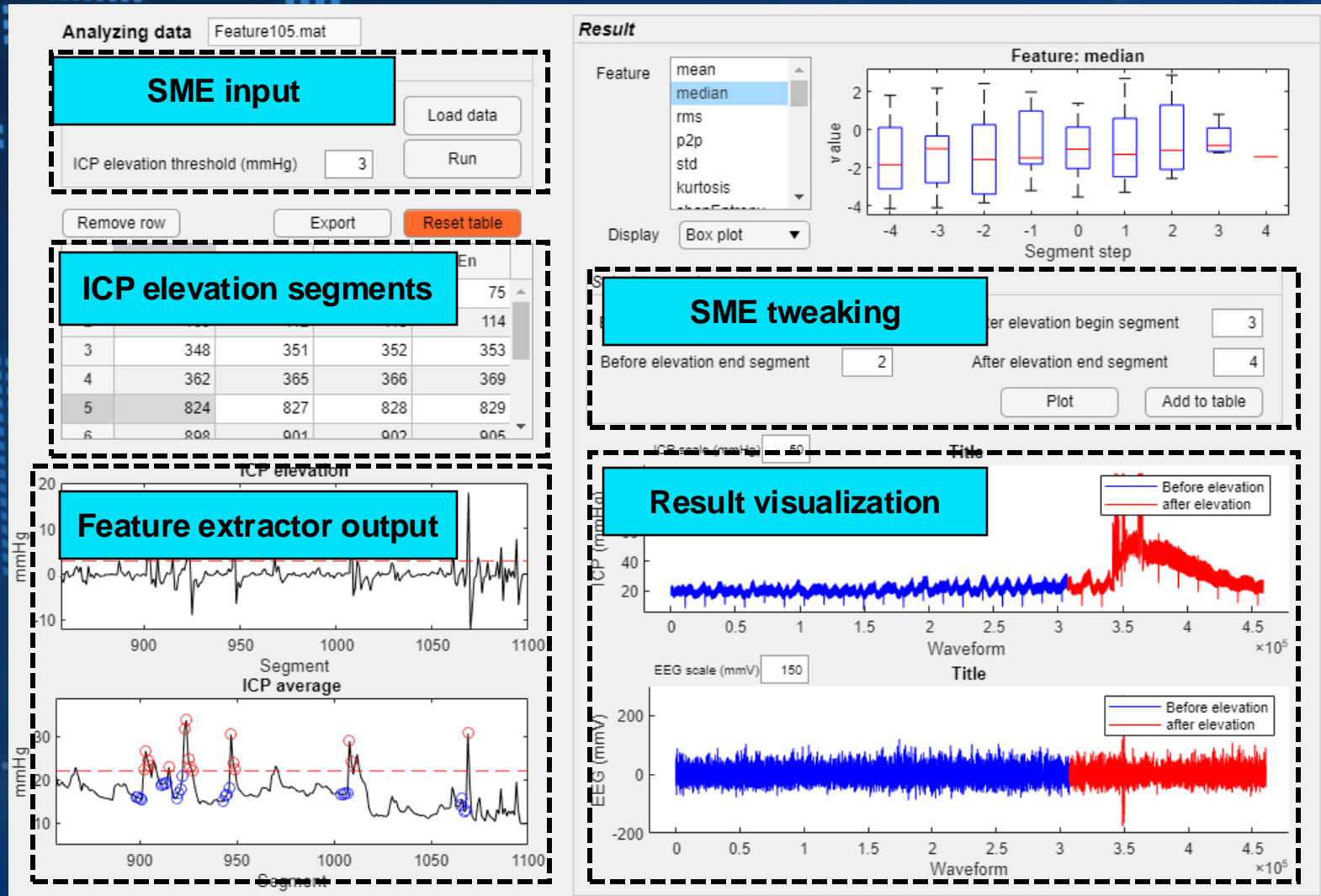
Challenges:

- Pattern changes on EEG along with ICP elevation is observable by Human Expert but hard to auto-detect by machine learning model due to high variances and unexpected artifact/noises
- The relationship between ischemic changes EEG and ICP elevation is intermittent and inconsistent
- Patterns among different patients are different.

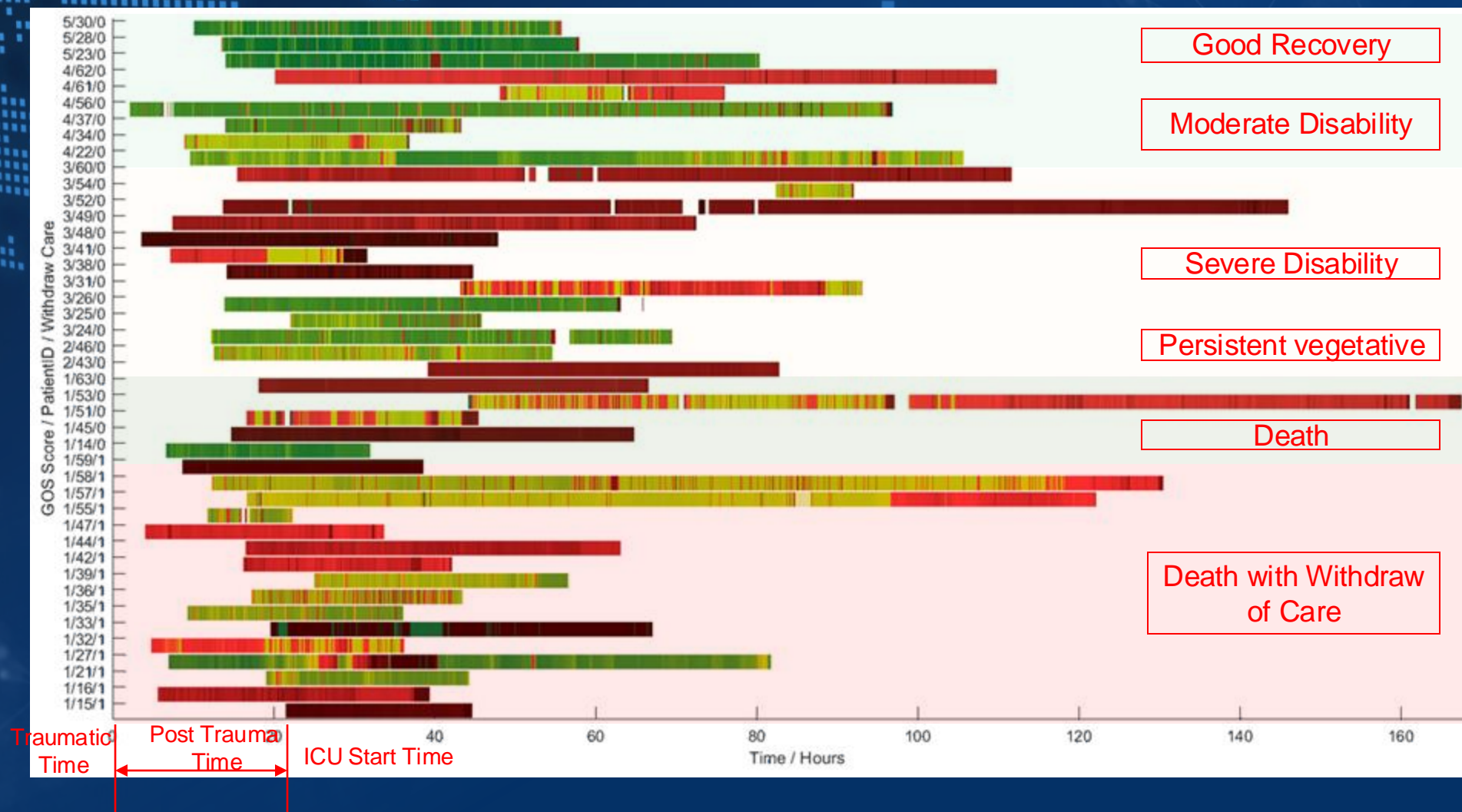
Domain-Augmented Human-AI Integration



ICP Elevation Segmentation- Human AI interaction UI



Health Assessment Results Summary of 43 ICU Patients



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Intracranial Pressure Monitoring Signals After Traumatic Brain Injury: A Narrative Overview and Conceptual Data Science Framework

 **Honghao Dai**^{1,2},  **Xiaodong Jia**^{1,2},  **Laura Pahren**^{1,2},  **Jay Lee**^{1,2} and  **Brandon Foreman**^{3*}

898

TOTAL VIEWS

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Outline

1. Trends of Data Centric Systems and Unmet Needs
2. Trends of AI and Industrial AI Systems
3. Some Examples
- 4. Training of New Breed of Industrial AI Engineers**



Memo to the President on U.S. Leadership in Advanced Manufacturing

2-2-2 AND NATSEC TECH BY SCSP
JUN 18



Key convergence technologies that are definitive for advanced manufacturing competitiveness include:

- **Industrial AI.** Thanks to its early lead in deploying generative AI, the United States appears well-positioned for AI deployment in the physical world. At present, much of the progress has been self-organizing: America is home to a variety of innovative startups and Fortune 500 companies that are either building or deploying industrial AI solutions in innovative ways. Yet, the United States is being substantially out-organized on a national level. This is especially reflected from a data perspective because the United States lacks large-scale national programs that encourage sharing of critical data sets needed to train industrial AI models across the private and public sectors.

2. Organize: Close Gaps in the Manufacturing Innovation Ecosystem.

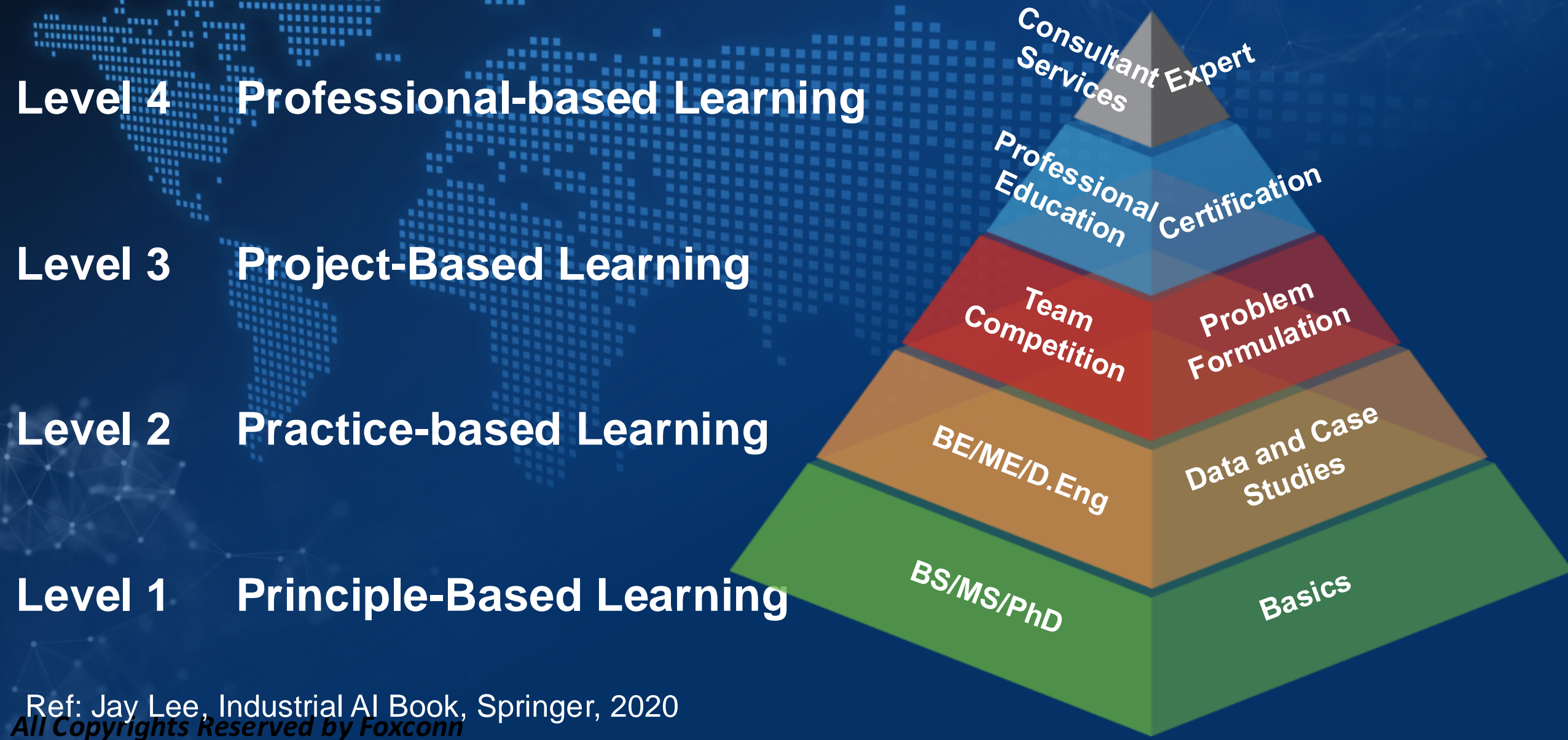
- Facilitate and strengthen key federal manufacturing programs.
- *Scale and Reimagine the Manufacturing Innovation Ecosystem.* The United States should redouble its support for its core manufacturing technology innovation programs, bringing resourcing for manufacturers more in line with spending by other industrialized nations.
- *Create a Data Foundry Network for Industrial AI.* A networked public-private partnership could serve as a trusted hub for companies to share necessary datasets to train sophisticated industrial AI models.
- *Establish a White House Office of Manufacturing.* A White House-level office would enhance policy coordination and bring urgency to the advanced manufacturing agenda.

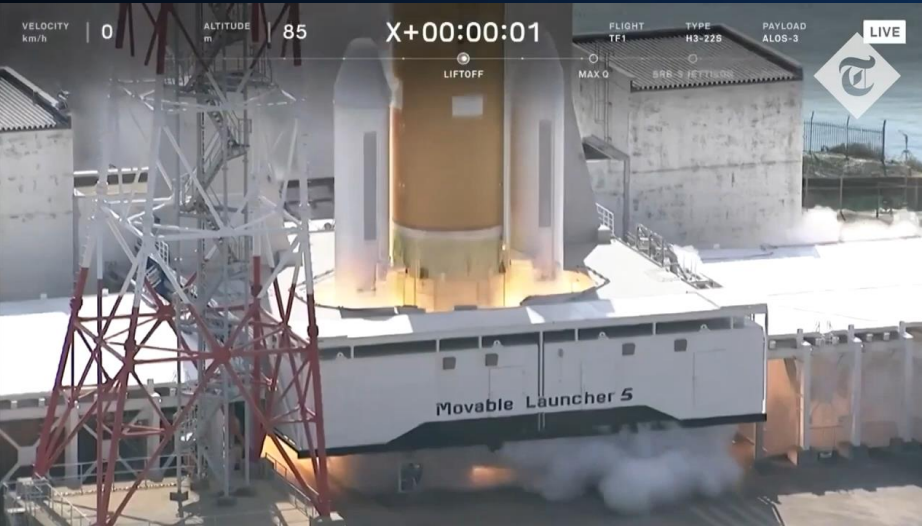
U.S. Needs to Lead and Excel Industrial AI with Speed and Scale.

Current Challenges of AI Talents

- 1. Hard to Find**
- 2. Can't Afford**
- 3. Hard to Keep**

4P Approach for AI Learning Enterprise

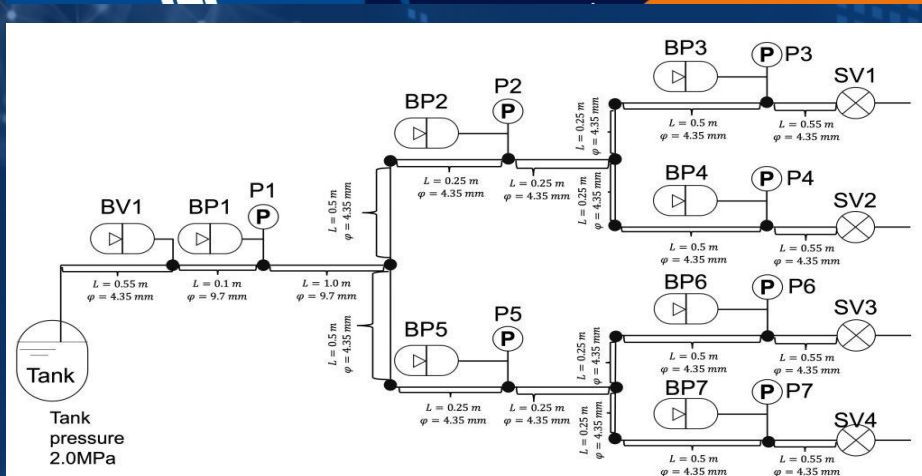




Launch of the First H3 Launch Vehicle (H3/TF1:Test Flight No.1) with Advanced Land Observing Satellite-3 "DAICHI-3" (ALOS-3) onboard

Live Stream

Broadcast: around 9:40 on Mar 7

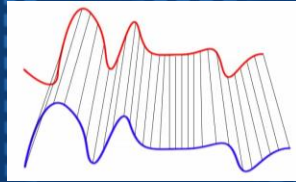
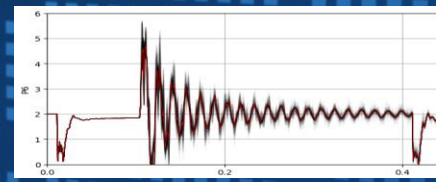


PHM AP Data Challenge 2023

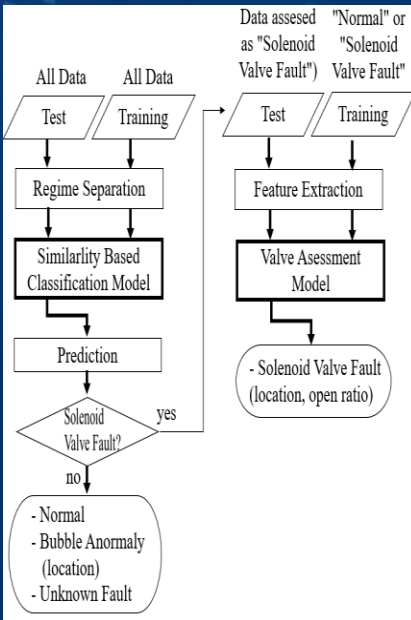
9/11-14, 2023



Approach



Dynamic Time Warping



Final Evaluation Result

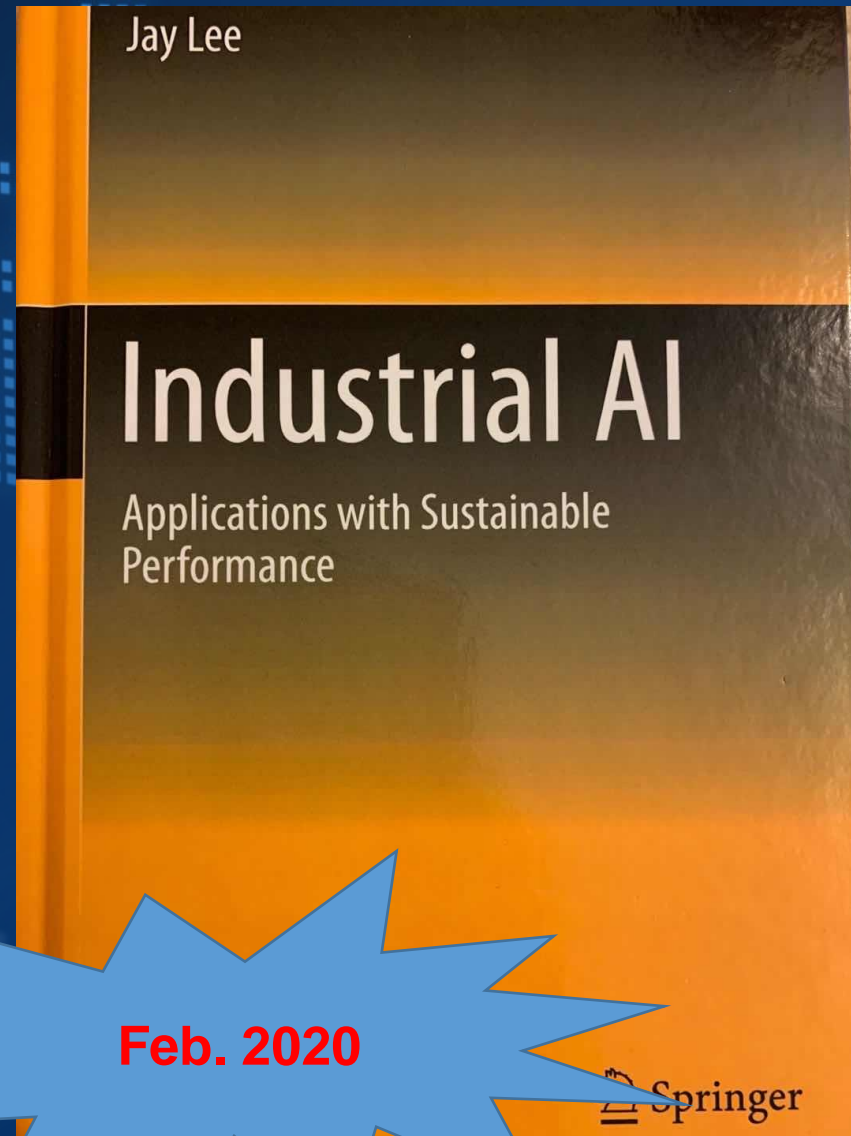
Team	Score
LB	100.00%
vibrationsensor	99.94%
SK	99.86%
Team Tsubasa	99.05%
KYU	97.26%
Kalle Anka PHM	93.77%
LDM	93.08%
MIDAS Wolverines	92.98%
Team HSNR	82.48%
propulsion	82.22%
JANUS	82.02%
CUMT	80.48%
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Bubu	76.44%
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tcs research	71.90%
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e-kagaku	61.49%
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Escape	60.12%
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**Takanobu
MINAMI**



“Industrial AI” Book



Feb. 2020

Thank You

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